TEXAS INSTRUMENTS
PCM1840
JAJSIT8 – APRIL 2019

PCM1840 クワッド・チャネル、32 ビット、192kHz、Burr-Brown™ オーディオ ADC

Texas Instruments Burr-Brown Audio

1 特長

- マルチチャネルの高性能 ADC
  - 4 チャネルのアナログ・マイクロフォンまたはライン入力
- ADC ラインおよびマイクロフォンの差動入力性能
  - ダイナミック・レンジ
    - ダイナミック・レンジ・エンハンサが有効な状態で 123dB
    - ダイナミック・レンジ・エンハンサが無効な状態で 113dB
  - THD+N：-98dB
- ADC 差動フルスケール入力：$2V_{RMS}$
- ADC サンプル・レート (f_S) ：8kHz～192kHz
- ハードウェア・ピン制御構成
- 線形位相または低レイテンシ・フィルタを選択可能
- 柔軟なオーディオ・シリアル・データ・インターフェイス
  - マスタまたはスレーブ・インターフェイスを選択可能
  - 32 ビット、4 チャネル TDM
  - 32 ビット、2 チャネル TDM
  - 32 ビット、2 チャネル I^2S
  - 32 ビット、2 チャネル LJ (左揃え)
- オーディオ・クロック喪失時の自動パワーダウン
- 高性能オーディオ PLL を内蔵
- 低ノイズ MICBIAS 2.75V 出力
- 単一電源動作：3.3V
- I/O 電源動作：3.3V または 1.8V
- 3.3V AVDD 電源での消費電力
  - 16kHz サンプル・レートで 17.0mW/ch
  - 48kHz サンプル・レートで 18.4mW/ch

2 アプリケーション

- スマート・スピーカー
- DVD レコーダおよびプレーヤ
- AV レシーバ
- テレビ会議システム
- IP ネットワーク・カメラ

3 概要

PCM1840 は、最大 4 つのアナログ・チャネルを同時にサンプリングできる高性能 Burr-Brown™オーディオ・アナログ / デジタル・コンバータ (ADC) です。本デバイスは、$2V_{RMS}$ フルスケール信号の差動ラインおよびマイクロフォン入力をサポートしています。マイクロフォン・バイアス電圧、位相ロック・ループ (PLL)、DC 除去ハイパス・フィルタ (HPF) を内蔵し、最高 192kHz のサンプル・レートに対応しています。TDM (時分割多重)、I^2S、LJ (左揃え) オーディオ・フォーマットをサポートしており、これらのフォーマットはハードウェア・ピンの入力レベルで選択できます。また PCM1840 は、オーディオ・バス・インターフェイス動作をマスタ・モードまたはスレーブ・モードに選択できます。これらの高性能な機能を内蔵し、かつ 3.3V 単一電源で動作できることから、本デバイスは、低コストと省スペースが求められる遠距離場マイクロフォン録音用途のオーディオ・システムに理想的な選択肢と言えます。

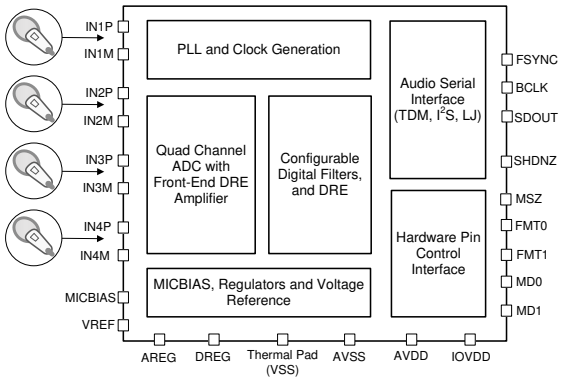
PCM1840 は –40℃～+125℃で動作が規定されており、24 ピンの WQFN パッケージで供給されます。

製品情報(1)

型番	パッケージ	本体サイズ(公称)
PCM1840	WQFN (24)	4.00mm × 4.00mm、0.5mm ピッチ

(1) 利用可能なすべてのパッケージについては、このデータシートの末尾にあるパッケージ・オプションについての付録を参照してください。

ブロック概略図



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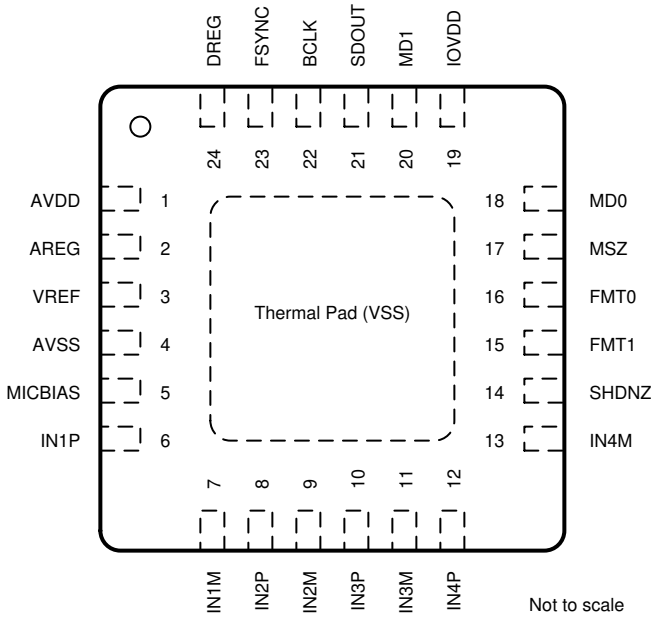
4 改訂履歴

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

日付	リビジョン	注
2020 年 4 月	*	初版

5 Pin Configuration and Functions

RTW Package
24-Pin WQFN With Exposed Thermal Pad
Top View



Pin Functions

PIN		TYPE	DESCRIPTION
NO.	NAME		
1	AVDD	Analog supply	Analog power (3.3 V, nominal)
2	AREG	Analog Supply	Analog on-chip regulator output voltage for analog supply (1.8 V, nominal)
3	VREF	Analog	Analog reference voltage filter output
4	AVSS	Analog supply	Analog ground. Short this pin directly to the board ground plane.
5	MICBIAS	Analog	MICBIAS output
6	IN1P	Analog input	Analog input 1P pin
7	IN1M	Analog input	Analog input 1M pin
8	IN2P	Analog input	Analog input 2P pin
9	IN2M	Analog input	Analog input 2M pin
10	IN3P	Analog input	Analog input 3P pin
11	IN3M	Analog input	Analog input 3M pin
12	IN4P	Analog input	Analog input 4P pin
13	IN4M	Analog input	Analog input 4M pin
14	SHDNZ	Digital input	Device hardware shutdown and reset (active low)
15	FMT1	Digital input	Audio interface format select 1 pin
16	FMT0	Digital input	Audio interface format select 0 pin
17	MSZ	Digital input	Audio interface bus master or slave select pin
18	MD0	Digital input	Device configuration mode select 0 pin
19	IOVDD	Digital supply	Digital I/O power supply (1.8 V or 3.3 V, nominal)
20	MD1	Digital input	Device configuration mode select 1 pin
21	SDOUT	Digital output	Audio serial data interface bus output
22	BCLK	Digital I/O	Audio serial data interface bus bit clock
23	FSYNC	Digital I/O	Audio serial data interface bus frame synchronization signal

Pin Functions (continued)

PIN		TYPE	DESCRIPTION
NO.	NAME		
24	DREG	Digital supply	Digital regulator output voltage for digital core supply (1.5 V, nominal)
Thermal Pad (VSS)		Ground supply	Thermal pad shorted to internal device ground. Short thermal pad directly to board ground plane.

6 Specifications

6.1 Absolute Maximum Ratings

over the operating ambient temperature range (unless otherwise noted)(1)

		MIN	MAX	UNIT
Supply voltage	AVDD to AVSS	–0.3	3.9	V
	AREG to AVSS	–0.3	2.0	
	IOVDD to VSS (thermal pad)	–0.3	3.9	
Ground voltage differences	AVSS to VSS (thermal pad)	–0.3	0.3	V
Analog input voltage	Analog input pins voltage to AVSS	–0.3	AVDD + 0.3	V
Digital input voltage	Digital input pins voltage to VSS (thermal pad)	–0.3	IOVDD + 0.3	V
Temperature	Operating ambient, T_A	–40	125	°C
	Junction, T_J	–40	150	
	Storage, T_{stg}	–65	150	

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001(1)	±2000	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101(2)	±500	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
POWER					
AVDD, AREG(1)	Analog supply voltage AVDD to AVSS (AREG is generated using onchip regulator) - AVDD 3.3-V operation	3.0	3.3	3.6	V
IOVDD	IO supply voltage to VSS (thermal pad) - IOVDD 3.3-V operation	3.0	3.3	3.6	V
	IO supply voltage to VSS (thermal pad) - IOVDD 1.8-V operation	1.65	1.8	1.95	
INPUTS					
	Analog input pins voltage to AVSS	0		AVDD	V
	Digital input pins voltage to VSS (thermal pad)	0		IOVDD	V
TEMPERATURE					
T_A	Operating ambient temperature	–40		125	°C
OTHERS					
	Digital input pin used as MCLK input clock frequency			36.864	MHz
C_L	Digital output load capacitance		20	50	pF

(1) AVSS and VSS (thermal pad): all ground pins must be tied together and must not differ in voltage by more than 0.2 V.

6.4 Thermal Information

THERMAL METRIC(1)		PCM1840 RTW (WQFN) 24 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	32.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	25.0	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	11.9	°C/W
ψ_{JT}	Junction-to-top characterization parameter	0.2	°C/W
ψ_{JB}	Junction-to-board characterization parameter	11.9	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	2.9	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report.

6.5 Electrical Characteristics

at T_A = 25°C, AVDD = 3.3 V, IOVDD = 3.3 V, f_{IN} = 1-kHz sinusoidal signal, f_S = 48 kHz, 32-bit audio data, BCLK = 256 × f_S, TDM slave mode (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
ADC CONFIGURATION						
	AC input impedance	Input pins INxP or INxM		2.5		kΩ
ADC PERFORMANCE FOR LINE/MICROPHONE INPUT RECORDING : AVDD 3.3-V OPERATION						
	Differential input full-scale AC signal voltage	AC-coupled input		2		V_{RMS}
SNR	Signal-to-noise ratio, A-weighted(1)(2)	IN1 differential input selected and AC signal shorted to ground, DRE enabled (DRE_LVL = –36 dB, DRE_MAXGAIN = 24 dB)	115	122		dB
		IN1 differential input selected and AC signal shorted to ground, DRE disabled	106	112		
DR	Dynamic range, A-weighted(2)	IN1 differential input selected and –60-dB full-scale AC signal input, DRE enabled (DRE_LVL = –36 dB, DRE_MAXGAIN = 24 dB)		123		dB
		IN1 differential input selected and –60-dB full-scale AC signal input, DRE disabled		113		
THD+N	Total harmonic distortion(2)(3)	IN1 differential input selected and –1-dB full-scale AC signal input, DRE enabled (DRE_LVL = –36 dB, DRE_MAXGAIN = 24 dB)		–98	–80	dB
		IN1 differential input selected and –1-dB full-scale AC signal input, DRE disabled		–98		
ADC OTHER PARAMETERS						
	Output data sample rate		7.35		192	kHz
	Output data sample word length				32	Bits
	Interchannel isolation	–1-dB full-scale AC-signal input to non measurement channel		–124		dB
	Interchannel gain mismatch	–6-dB full-scale AC-signal input		0.1		dB
	Gain drift	across temperature range 15°C to 35°C		–4.4		ppm/°C
	Interchannel phase mismatch	1-kHz sinusoidal signal		0.02		Degrees
	Phase drift	1-kHz sinusoidal signal, across temperature range 15°C to 35°C		0.0005		Degrees/°C
PSRR	Power-supply rejection ratio	100-mV_{PP}, 1-kHz sinusoidal signal on AVDD, differential input selected, 0-dB channel gain		102		dB
CMRR	Common-mode rejection ratio	Differential microphone input selected, 100-mV_{PP}, 1-kHz signal on both pins and measure level at output		60		dB

(1) Ratio of output level with 1-kHz full-scale sine-wave input, to the output level with the AC signal input shorted to ground, measured A-weighted over a 20-Hz to 20-kHz bandwidth using an audio analyzer.
(2) All performance measurements done with 20-kHz low-pass filter and, where noted, A-weighted filter. Failure to use such a filter may result in higher THD and lower SNR and dynamic range readings than shown in the Electrical Characteristics. The low-pass filter removes out-of-band noise, which, although not audible, may affect dynamic specification values.
(3) For best distortion performance, use input AC-coupling capacitors with low-voltage-coefficient.

Electrical Characteristics (continued)

at T_A = 25°C, AVDD = 3.3 V, IOVDD = 3.3 V, f_{IN} = 1-kHz sinusoidal signal, f_S = 48 kHz, 32-bit audio data, BCLK = 256 × f_S, TDM slave mode (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
MICROPHONE BIAS						
	MICBIAS noise	BW = 20 Hz to 20 kHz, A-weighted, 1-µF capacitor between MICBIAS and AVSS		1.6		μV_{RMS}
	MICBIAS voltage			VREF		V
	MICBIAS current drive				20	mA
	MICBIAS load regulation	Measured up to max load	0.1	0.6	1.8	%
	MICBIAS over current protection threshold		30			mA
DIGITAL I/O						
V_{IL}	Low-level digital input logic voltage threshold	All digital pins, IOVDD 1.8-V operation	–0.3		0.30 × IOVDD	V
		All digital pins, IOVDD 3.3-V operation	–0.3		0.8	
V_{IH}	High-level digital input logic voltage threshold	All digital pins, IOVDD 1.8-V operation	0.7 × IOVDD		IOVDD + 0.3	V
		All digital pins, IOVDD 3.3-V operation	2.1		IOVDD + 0.3	
V_{OL}	Low-level digital output voltage	All digital pins, I_{OL} = –2 mA, IOVDD 1.8-V operation			0.45	V
		All digital pins, I_{OL} = –2 mA, IOVDD 3.3-V operation			0.4	
V_{OH}	High-level digital output voltage	All digital pins, I_{OH} = 2 mA, IOVDD 1.8-V operation	IOVDD – 0.45			V
		All digital pins, I_{OH} = 2 mA, IOVDD 3.3-V operation	2.4			
I_{IH}	Input logic-high leakage for digital inputs	All digital pins, input = IOVDD	–5	0.1	5	µA
I_{IL}	Input logic-low leakage for digital inputs	All digital pins, input = 0 V	–5	0.1	5	µA
C_{IN}	Input capacitance for digital inputs	All digital pins		5		pF
R_{PD}	Pulldown resistance for digital I/O pins when asserted on			20		kΩ
TYPICAL SUPPLY CURRENT CONSUMPTION						
I_{AVDD}	Current consumption in hardware shutdown mode	SHDNZ = 0, AVDD = 3.3 V, internal AREG		0.5		µA
I_{IOVDD}		SHDNZ = 0, all external clocks stopped, IOVDD = 3.3 V		0.1		
I_{IOVDD}		SHDNZ = 0, all external clocks stopped, IOVDD = 1.8 V		0.1		
I_{AVDD}	Current consumption with ADC 4-channel operating at f_S 16-kHz, BCLK = 256 × f_S and DRE disable	AVDD = 3.3 V, internal AREG		20.6		mA
I_{IOVDD}		IOVDD = 3.3 V		0.05		
I_{IOVDD}		IOVDD = 1.8 V		0.02		
I_{AVDD}	Current consumption with ADC 4-channel operating at f_S 48-kHz, BCLK = 256 × f_S and DRE disable	AVDD = 3.3 V, internal AREG		22.3		mA
I_{IOVDD}		IOVDD = 3.3 V		0.1		
I_{IOVDD}		IOVDD = 1.8 V		0.05		
I_{AVDD}	Current consumption with ADC 4-channel operating at f_S 48-kHz, BCLK = 256 × f_S and DRE enable	AVDD = 3.3 V, internal AREG		24.4		mA
I_{IOVDD}		IOVDD = 3.3 V		0.1		
I_{IOVDD}		IOVDD = 1.8 V		0.05		

6.6 Timing Requirements: TDM, I²S or LJ Interface

at T_A = 25°C, IOVDD = 3.3 V or 1.8 V and 20-pF load on all outputs (unless otherwise noted); see Figure 3 for timing diagram

			MIN	NOM	MAX	UNIT
$t_{(BCLK)}$	BCLK period		40			ns
$t_{H(BCLK)}$	BCLK high pulse duration (1)		18			ns
$t_{L(BCLK)}$	BCLK low pulse duration (1)		18			ns
$t_{SU(FSYNC)}$	FSYNC setup time		8			ns
$t_{HLD(FSYNC)}$	FSYNC hold time		8			ns
$t_{r(BCLK)}$	BCLK rise time	10% - 90% rise time			10	ns
$t_{f(BCLK)}$	BCLK fall time	90% - 10% fall time			10	ns

(1) The BCLK minimum high or low pulse duration must be higher than 25 ns (to meet the timing specifications), if the SDOUT data line is latched on the opposite BCLK edge polarity than the edge used by the device to transmit SDOUT data.

6.7 Switching Characteristics: TDM, I²S or LJ Interface

at T_A = 25°C, IOVDD = 3.3 V or 1.8 V and 20-pF load on all outputs (unless otherwise noted); see Figure 3 for timing diagram

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$t_{d(SDOUT-BCLK)}$	BCLK to SDOUT delay	50% of BCLK to 50% of SDOUT			18	ns
$t_{d(SDOUT-FSYNC)}$	FSYNC to SDOUT delay in TDM or LJ mode (for MSB data with TX_OFFSET = 0)	50% of FSYNC to 50% of SDOUT			18	ns
$f_{(BCLK)}$	BCLK output clock frequency: master mode (1)				24.576	MHz
$t_{H(BCLK)}$	BCLK high pulse duration: master mode		14			ns
$t_{L(BCLK)}$	BCLK low pulse duration: master mode		14			ns
$t_{d(FSYNC)}$	BCLK to FSYNC delay: master mode	50% of BCLK to 50% of FSYNC			18	ns
$t_{r(BCLK)}$	BCLK rise time: master mode	10% - 90% rise time			8	ns
$t_{f(BCLK)}$	BCLK fall time: master mode	90% - 10% fall time			8	ns

(1) The BCLK output clock frequency must be lower than 18.5 MHz (to meet the timing specifications), if the SDOUT data line is latched on the opposite BCLK edge polarity than the edge used by the device to transmit SDOUT data.

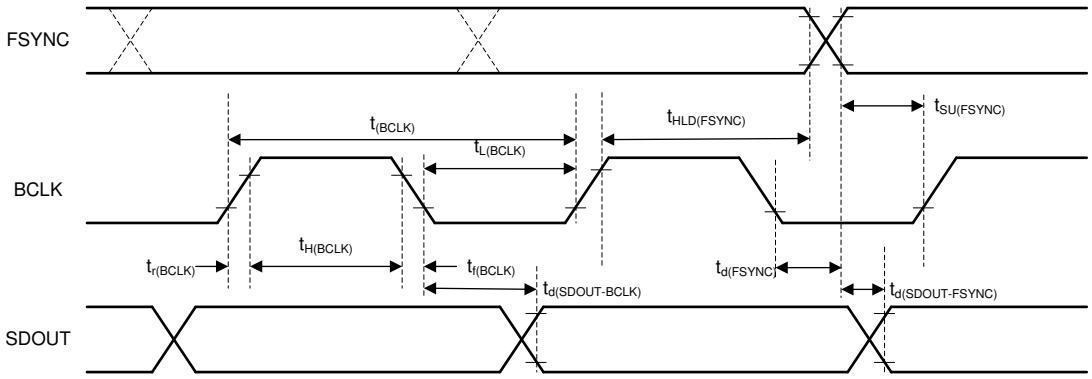


図 1. TDM, I²S, and LJ Interface Timing Diagram

6.8 Typical Characteristics

at T_A = 25°C, AVDD = 3.3 V, IOVDD = 3.3 V, f_{IN} = 1-kHz sinusoidal signal, f_S = 48 kHz, 32-bit audio data, BCLK = 256 × f_S, TDM slave mode, PLL on, DRE_LVL = –36 dB, channel gain = 0 dB, and linear phase decimation filter (unless otherwise noted); all performance measurements are done with a 20-kHz, low-pass filter, and an A-weighted filter

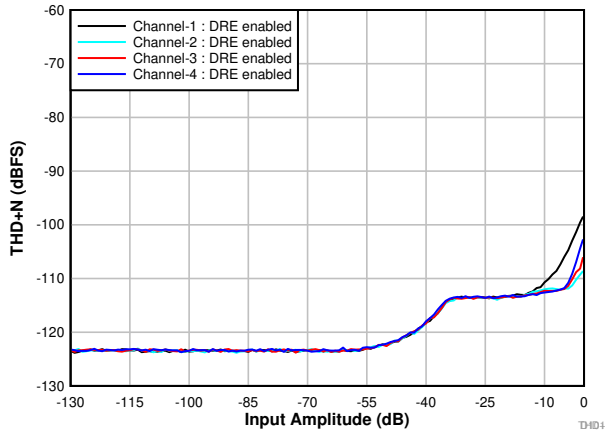


図 2. THD+N vs Input Amplitude With DRE Enabled

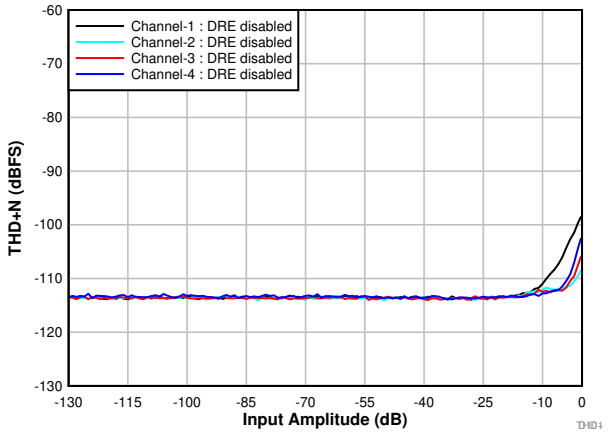


図 3. THD+N vs Input Amplitude With DRE Disabled

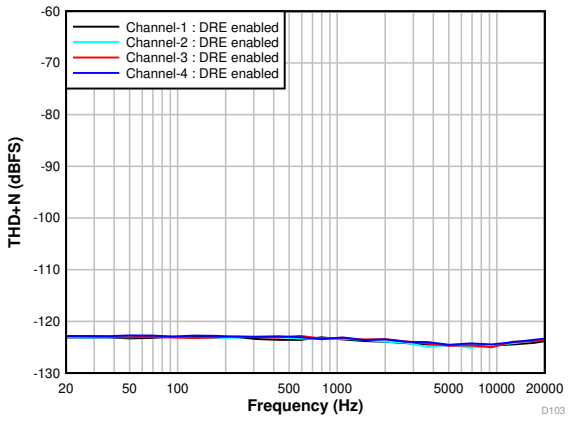


図 4. THD+N vs Input Frequency With a –60-dBr Input

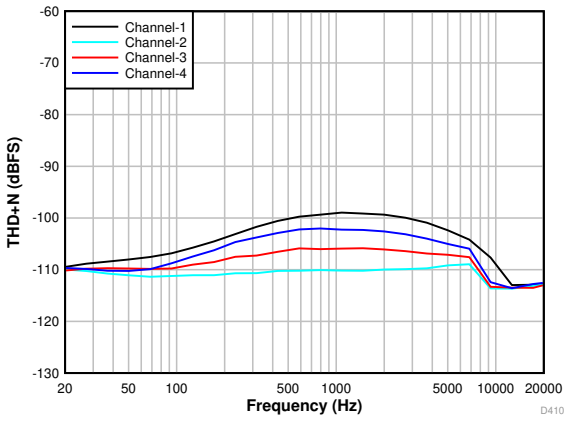


図 5. THD+N vs Input Frequency With a –1-dBr Input

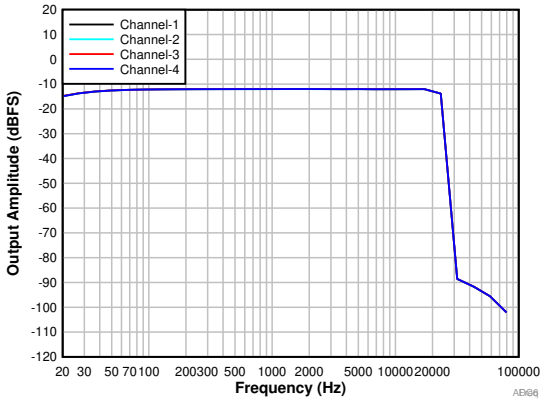


図 6. Frequency Response With a –12-dBr Input

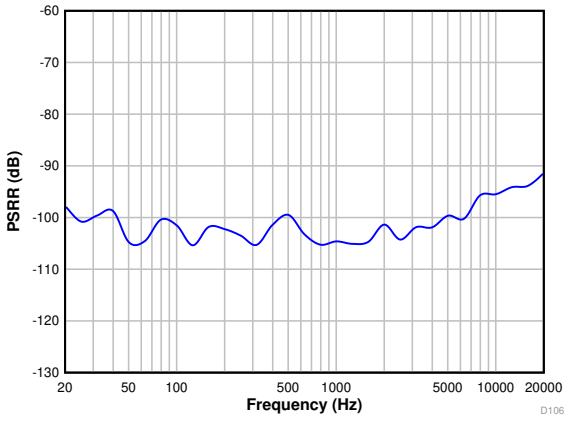


図 7. Power-Supply Rejection Ratio vs Ripple Frequency With 100-mV_{PP} Amplitude

Typical Characteristics (continued)

at T_A = 25°C, AVDD = 3.3 V, IOVDD = 3.3 V, f_{IN} = 1-kHz sinusoidal signal, f_S = 48 kHz, 32-bit audio data, BCLK = 256 × f_S, TDM slave mode, PLL on, DRE_LVL = –36 dB, channel gain = 0 dB, and linear phase decimation filter (unless otherwise noted); all performance measurements are done with a 20-kHz, low-pass filter, and an A-weighted filter

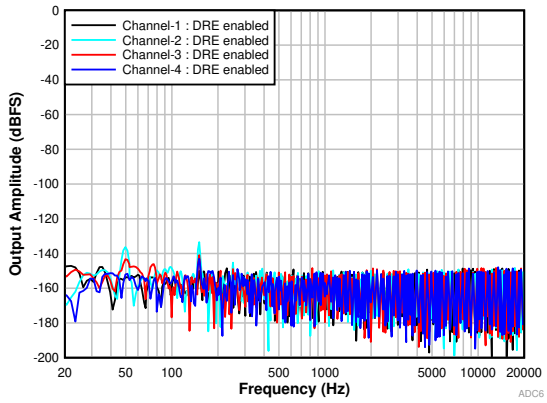


図 8. FFT With Idle Input With DRE Enabled

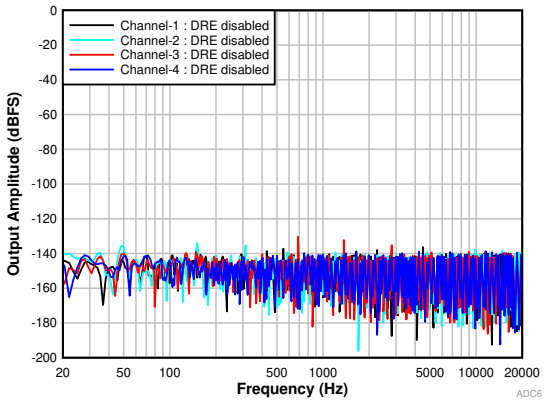


図 9. FFT With Idle Input With DRE Disabled

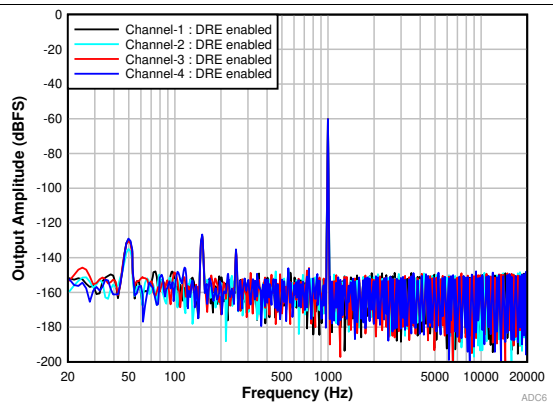


図 10. FFT With a –60-dBr Input With DRE Enabled

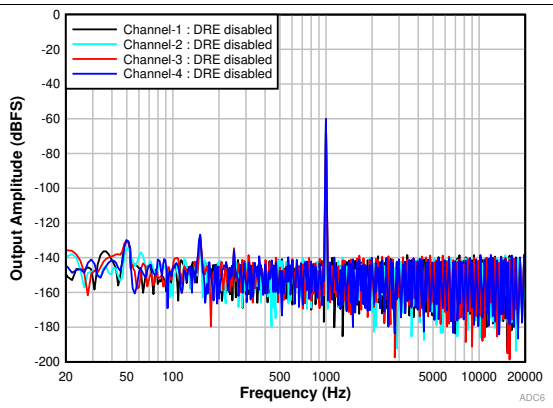


図 11. FFT With a –60-dBr Input With DRE Disabled

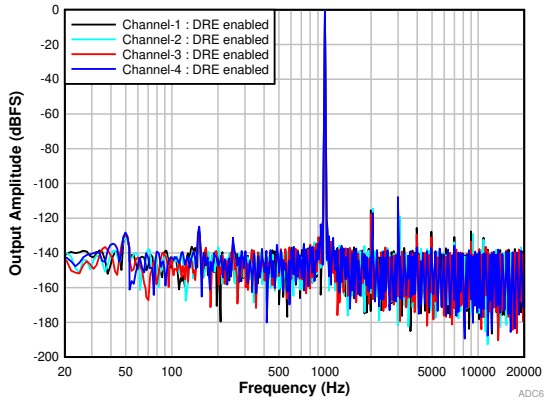


図 12. FFT With a –1-dBr Input With DRE Enabled

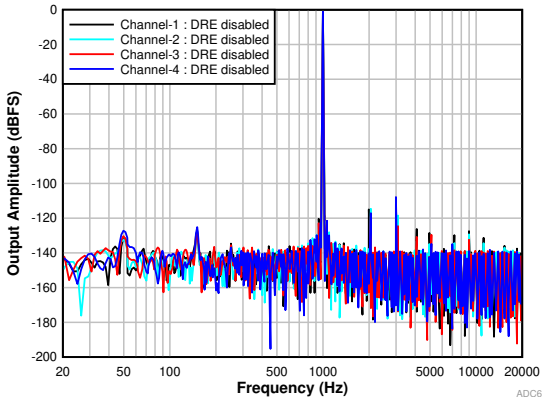


図 13. FFT With a –1-dBr Input With DRE Disabled

7 Detailed Description

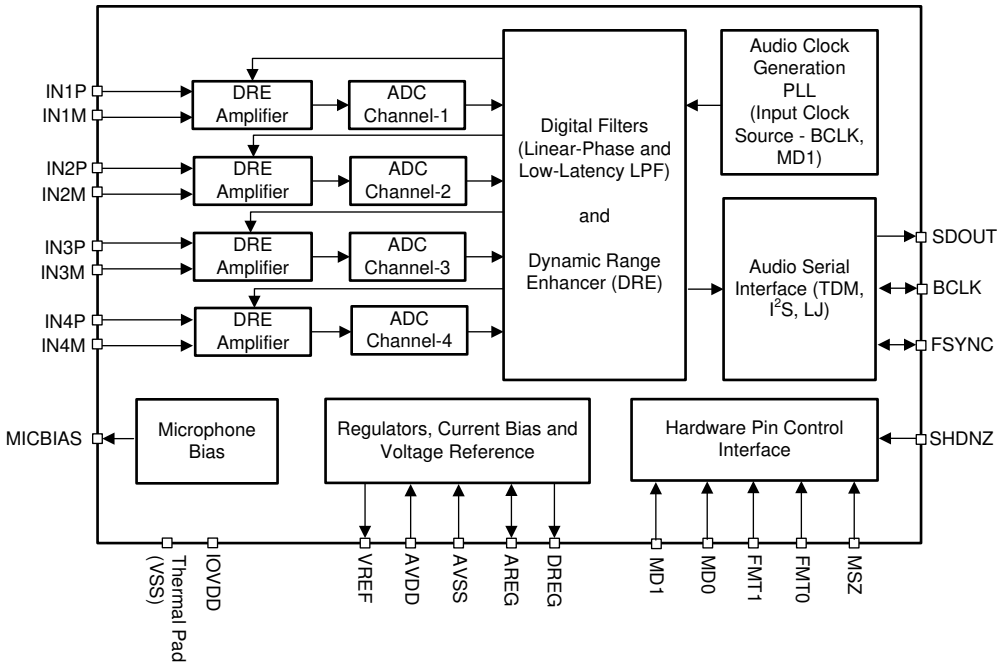
7.1 Overview

The PCM1840 is a high-performance, low-power, quad-channel, audio analog-to-digital converter (ADC) with flexible audio interface control options. This device is intended for applications in voice-activated systems, AV receivers, TV and blu-ray players, professional microphones, audio conferencing, portable computing, communication, and entertainment applications. The high dynamic range of the device enables far-field audio recording with high fidelity. This device integrates a host of features that reduces cost, board space, and power consumption in space-constrained, battery-powered, consumer, home, and industrial applications. The device features are controlled through hardware by pulling pins high or low with resistors or a controller GPIO. The PCM1808 also supports a power-down and reset function by means of halting the system clock.

The PCM1840 consists of the following blocks and features:

- Quad-channel, multibit, high-performance delta-sigma (ΔΣ) ADC
- Differential audio inputs with a 2-V_{RMS} full-scale signal
- Low-noise, 1.6-μV_{RMS}, microphone bias output
- Hardware pin control operation to select the device features
- Audio bus serial interface master or slave select option
- Audio bus serial interface format select option
- Audio bus serial interface supported up to 192 kHz sampling
- Slave mode supports dynamic range enhancer (DRE) with 123-dB dynamic range
- Slave mode supports decimation filters with linear-phase or low-latency filter selection
- Master mode operation supported using system clock of 256 × f_S or 512 × f_S
- Power-down function by means of halting the audio clocks
- Integrated high-pass filter (HPF) that removes the dc component of the input signal
- Integrated low-jitter phase-locked loop (PLL) supporting a wide range of system clocks
- Integrated digital and analog voltage regulators to support single-supply 3.3-V operation

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Hardware Control

The device supports simple hardware pin controlled options to select specific mode of operation and audio interface for a given system. The MSZ, MD0, MD1, FMT0, and FMT1 pins allow the device to be controlled by either pullup or pulldown resistors as well as the GPIO from a digital device.

7.3.2 Audio Serial Interfaces

Digital audio data flows between the host processor and the PCM1840 on the digital audio serial interface (ASI), or audio bus. This highly flexible ASI bus includes a TDM mode for multichannel operation, support for I^2S or left-justified protocols format, and the pin-selectable master-slave configurability for bus clock lines.

The device supports audio bus master or slave mode of operation using the hardware pin MSZ. In slave mode, FSYNC and BCLK work as input pins whereas in master mode, FSYNC and BCLK work as output pins generated by the device.表 1 shows the master and slave mode selection using the MSZ pin.

表 1. Master and Slave Mode Selection

MSZ	MASTER AND SLAVE SELECTION
LOW	Slave mode of operation
HIGH	Master ode of operation

The bus protocol TDM, I^2S, or left-justified (LJ) format can be selected by using the FMT0 and FMT1 pins. As shown in 表 2, these modes are all most significant byte (MSB)-first, pulse code modulation (PCM) data format, with the output channel data word-length of 32 bits.

表 2. Audio Serial Interface Format

FMT1	FMT0	AUDIO SERIAL INTERFACE FORMAT
LOW	LOW	4-channel output with time division multiplexing (TDM) mode
LOW	HIGH	2-channel output with time division multiplexing (TDM) mode
HIGH	LOW	2-channel output with left-justified (LJ) mode
HIGH	HIGH	2-channel output with inter IC sound (I^2S) mode

7.3.2.1 Time Division Multiplexed Audio (TDM) Interface

In TDM mode, also known as DSP mode, the rising edge of FSYNC starts the data transfer with the slot 0 data first. Immediately after the slot 0 data transmission, the remaining slot data are transmitted in order. FSYNC and each data bit (except the MSB of slot 0 when TX_OFFSET equals 0) is transmitted on the rising edge of BCLK. 図 14 to 図 17 illustrate the protocol timing for TDM operation with various configurations.

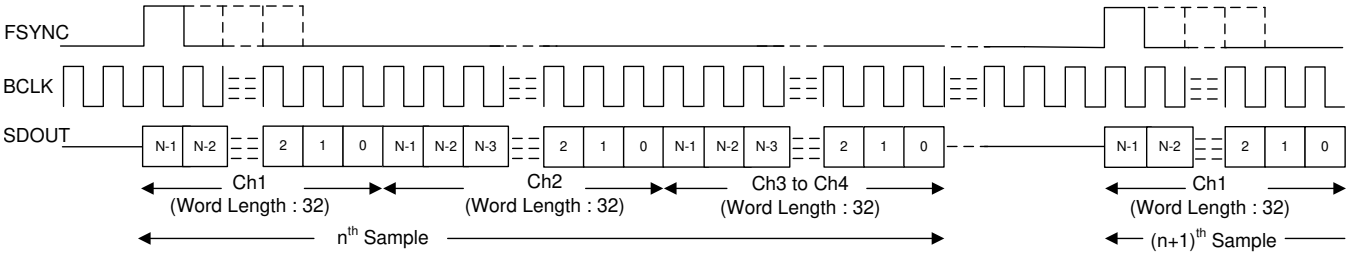


図 14. TDM Mode Protocol Timing (FMT0 = LOW) In Slave Mode

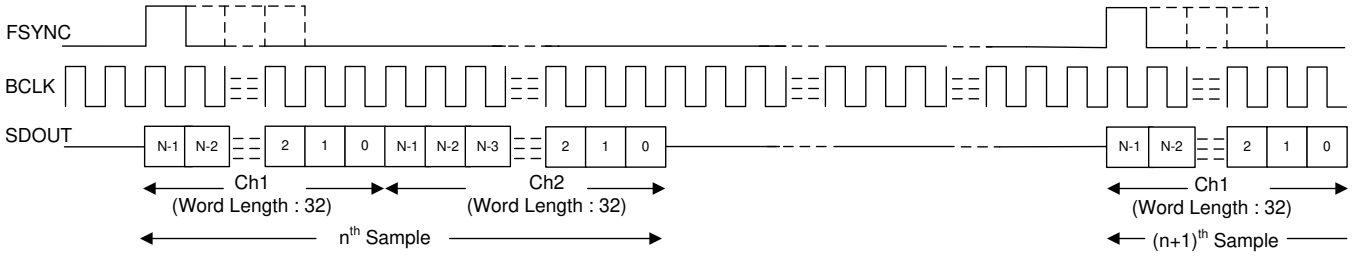


図 15. TDM Mode Protocol Timing (FMT0 = HIGH) In Slave Mode

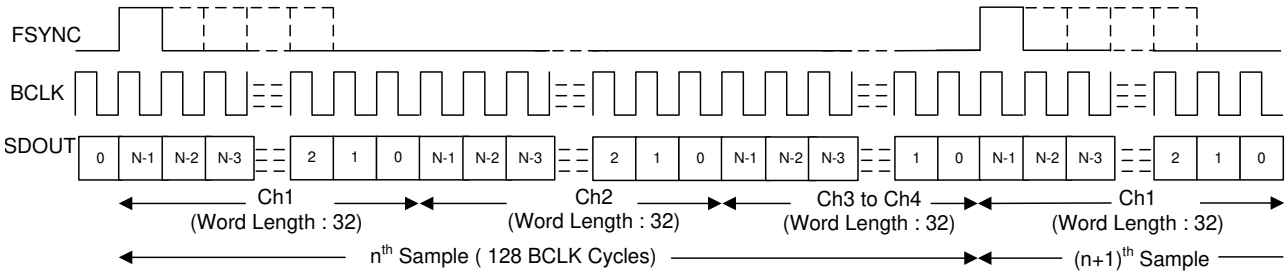


図 16. TDM Mode Protocol Timing (FMT0 = LOW) In Master Mode

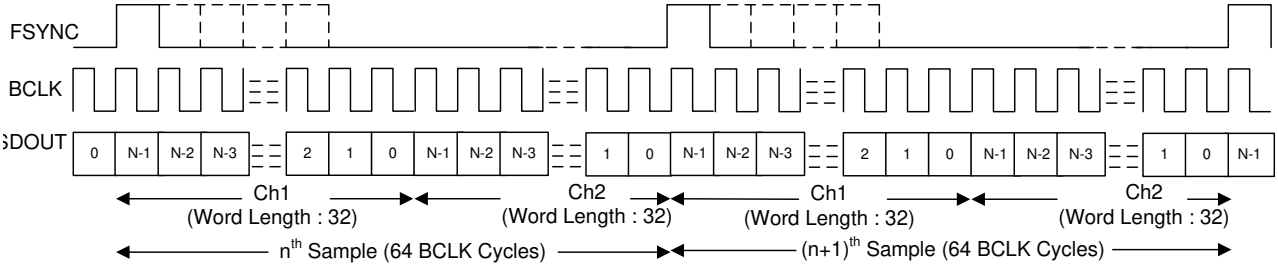


図 17. TDM Mode Protocol Timing (FMT0 = HIGH) In Master Mode

For proper operation of the audio bus in TDM mode, the number of bit clocks per frame must be greater than or equal to the number of active output channels times the 32-bits word length of the output channel data. The device transmits a zero data value on SDOUT for the extra unused bit clock cycles. The device supports FSYNC as a pulse with a 1-cycle-wide bit clock, but also supports multiples as well.

7.3.2.2 Inter IC Sound (I^2S) Interface

The standard I^2S protocol is defined for only two channels: left and right. In I^2S mode, the MSB of the left slot 0 is transmitted on the falling edge of BCLK in the second cycle after the *falling* edge of FSYNC. The MSB of the right slot 0 is transmitted on the falling edge of BCLK in the second cycle after the *rising* edge of FSYNC. Each subsequent data bit is transmitted on the falling edge of BCLK. In master mode, FSYNC is transmitted on the rising edge of BCLK. 図 18 and 図 19 illustrate the protocol timing for I^2S operation in slave and master mode of operation.

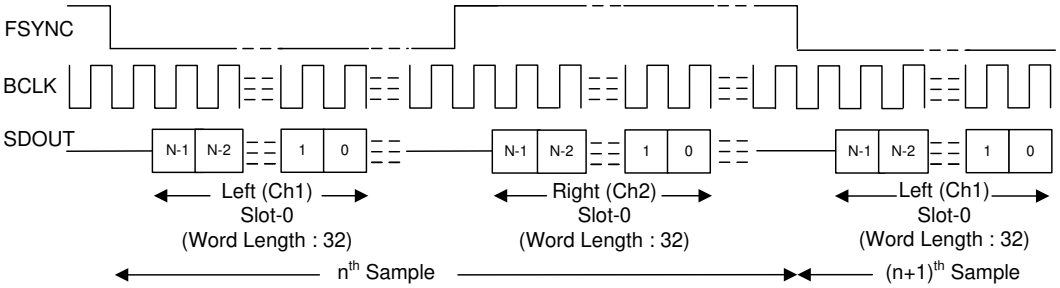


図 18. I²S Mode Protocol Timing in Slave Mode

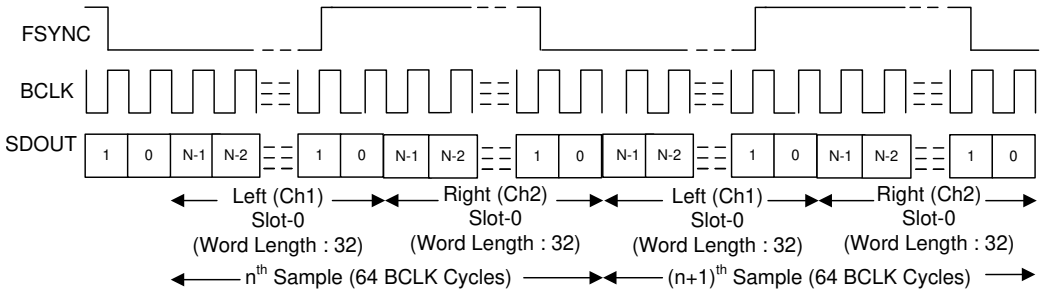


図 19. I²S Protocol Timing In Master Mode

For proper operation of the audio bus in I²S mode, the number of bit clocks per frame must be greater than or equal to the number of active output channels (including left and right slots) times the 32-bits word length of the output channel data. The device FSYNC low pulse must be a number of BCLK cycles wide that is greater than or equal to the number of active left slots times the 32-bits data word length. Similarly, the FSYNC high pulse must be a number of BCLK cycles wide that is greater than or equal to the number of active right slots times the 32-bits data word length. The device transmit zero data value on SDOUT for the extra unused bit clock cycles.

7.3.2.3 Left-Justified (LJ) Interface

The standard LJ protocol is defined for only two channels: left and right. In LJ mode, the MSB of the left slot 0 is transmitted in the same BCLK cycle after the *rising* edge of FSYNC. Each subsequent data bit is transmitted on the falling edge of BCLK. The MSB of the right slot 0 is transmitted in the same BCLK cycle after the *falling* edge of FSYNC. Each subsequent data bit is transmitted on the falling edge of BCLK. In master mode, FSYNC is transmitted on the rising edge of BCLK. 図 20 and 図 21 illustrate the protocol timing for LJ operation in slave and master mode of operation.

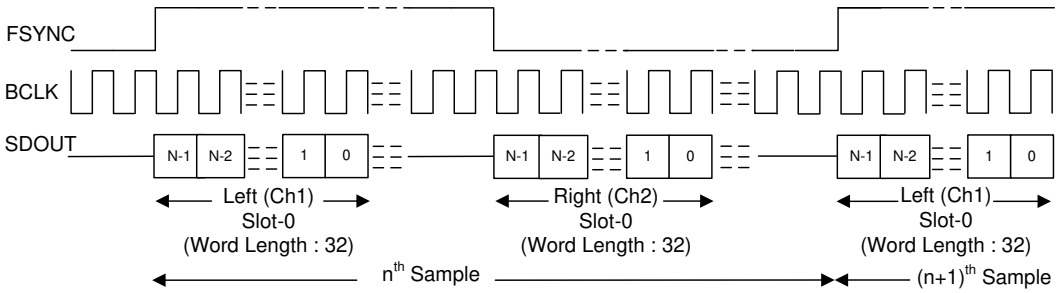


図 20. LJ Mode Protocol Timing In Slave Mode

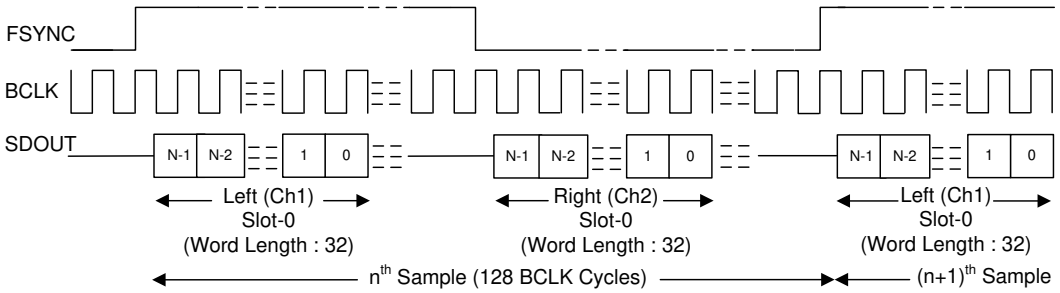


図 21. LJ Mode Protocol Timing In Master Mode

For proper operation of the audio bus in LJ mode, the number of bit clocks per frame must be greater than or equal to the number of active output channels (including left and right slots) times the 32-bits word length of the output channel data. The device FSYNC high pulse must be a number of BCLK cycles wide that is greater than or equal to the number of active left slots times the 32-bits data word length. Similarly, the FSYNC low pulse must be number of BCLK cycles wide that is greater than or equal to the number of active right slots times the 32-bits data word length. The device transmit zero data value on SDOUT for the extra unused bit clock cycles.

7.3.3 Phase-Locked Loop (PLL) and Clock Generation

The device uses an integrated, low-jitter, phase-locked loop (PLL) to generate internal clocks required for the ADC modulator and digital filter engine, as well as other control blocks.

In slave mode of operation, the device supports the various output data sample rates (of the FSYNC signal frequency) and the BCLK to FSYNC ratio to configure all clock dividers, including the PLL configuration, internally without host programming. 表 3 and 表 4 list the supported FSYNC and BCLK frequencies.

表 3. Supported FSYNC (Multiples or Submultiples of 48 kHz) and BCLK Frequencies

BCLK TO FSYNC RATIO	BCLK (MHz)						
	FSYNC (8 kHz)	FSYNC (16 kHz)	FSYNC (24 kHz)	FSYNC (32 kHz)	FSYNC (48 kHz)	FSYNC (96 kHz)	FSYNC (192 kHz)
16	Reserved	0.256	0.384	0.512	0.768	1.536	3.072
24	Reserved	0.384	0.576	0.768	1.152	2.304	4.608
32	0.256	0.512	0.768	1.024	1.536	3.072	6.144
48	0.384	0.768	1.152	1.536	2.304	4.608	9.216
64	0.512	1.024	1.536	2.048	3.072	6.144	12.288
96	0.768	1.536	2.304	3.072	4.608	9.216	18.432
128	1.024	2.048	3.072	4.096	6.144	12.288	24.576
192	1.536	3.072	4.608	6.144	9.216	18.432	Reserved
256	2.048	4.096	6.144	8.192	12.288	24.576	Reserved
384	3.072	6.144	9.216	12.288	18.432	Reserved	Reserved
512	4.096	8.192	12.288	16.384	24.576	Reserved	Reserved

表 4. Supported FSYNC (Multiples or Submultiples of 44.1 kHz) and BCLK Frequencies

BCLK TO FSYNC RATIO	BCLK (MHz)						
	FSYNC (7.35 kHz)	FSYNC (14.7 kHz)	FSYNC (22.05 kHz)	FSYNC (29.4 kHz)	FSYNC (44.1 kHz)	FSYNC (88.2 kHz)	FSYNC (176.4 kHz)
16	Reserved	Reserved	0.3528	0.4704	0.7056	1.4112	2.8224
24	Reserved	0.3528	0.5292	0.7056	1.0584	2.1168	4.2336
32	Reserved	0.4704	0.7056	0.9408	1.4112	2.8224	5.6448
48	0.3528	0.7056	1.0584	1.4112	2.1168	4.2336	8.4672
64	0.4704	0.9408	1.4112	1.8816	2.8224	5.6448	11.2896
96	0.7056	1.4112	2.1168	2.8224	4.2336	8.4672	16.9344
128	0.9408	1.8816	2.8224	3.7632	5.6448	11.2896	22.5792
192	1.4112	2.8224	4.2336	5.6448	8.4672	16.9344	Reserved
256	1.8816	3.7632	5.6448	7.5264	11.2896	22.5792	Reserved
384	2.8224	5.6448	8.4672	11.2896	16.9344	Reserved	Reserved
512	3.7632	7.5264	11.2896	15.0528	22.5792	Reserved	Reserved

In the master mode of operation, the device uses the MD1 pin (as system clock, MCLK) as the reference input clock source with supported system clock frequency option of either 256 × f_S or 512 × f_S as configured using the MD0 pin. 表 5 shows the system clock selection for the master mode using the MD0 pin.

表 5. System Clock Selection for the Master Mode

MD0	SYSTEM CLOCK SELECTION (Valid for Master Mode Only)
LOW	System clock with frequency 256 × f_S connected to pin MD1 as MCLK
HIGH	System clock with frequency 512 × f_S connected to pin MD1 as MCLK

See 表 7 and 表 20 for the MD0 and MD1 pin function in the slave mode of operation.

7.3.4 Input Channel Configurations

The device consists of four pairs of analog input pins (INxP and INxM) as differential inputs for the recording channel. The device supports simultaneous recording of up to four channels using the high-performance multichannel ADC. The input source for the analog pins can be from electret condenser analog microphones, micro electrical-mechanical system (MEMS) analog microphones, or line-in (auxiliary) inputs from the system board.

The voice or audio signal inputs must be capacitively coupled (AC-coupled) to the device and for best distortion performance, use the low-voltage coefficient capacitors for AC coupling. The device has the typical input impedance on INxP or INxM as 2.5 kΩ on each pins. The value of the coupling capacitor in AC-coupled mode must be chosen so that the high-pass filter formed by the coupling capacitor and the input impedance do not affect the signal content. Before proper recording can begin, this coupling capacitor must be charged up to the common-mode voltage at power-up. To enable quick charging, the device has quick charge scheme to speed up the charging of the coupling capacitor at power-up. The default value of the quick-charge timing is set for a coupling capacitor up to 1 µF.

7.3.5 Reference Voltage

All audio data converters require a DC reference voltage. The PCM1840 achieves low-noise performance by internally generating a low-noise reference voltage. This reference voltage is generated using a band-gap circuit with high PSRR performance. This audio converter reference voltage must be filtered externally using a minimum 1-µF capacitor connected from the VREF pin to analog ground (AVSS). The value of this reference voltage, VREF, is set to 2.75 V, which in turn supports a 2-V_{RMS} differential full-scale input to the device. The required minimum AVDD voltage for this VREF voltage is 3 V. Do not connect any external load to a VREF pin.

7.3.6 Microphone Bias

The device integrates a built-in, low-noise, 1.6-μV_{RMS} microphone bias pin with an output voltage of 2.75 V that can be used in the system for biasing electret-condenser microphones or providing the supply to the MEMS analog or digital microphone. The integrated bias amplifier supports up to 20 mA of load current that can be used for multiple microphones and is designed to provide a combination of high PSRR, and low noise bias voltages to bias microphone for high-end audio applications. When using this MICBIAS pin for biasing or supplying to multiple microphones, avoid any common impedance on the board layout for the MICBIAS connection to minimize coupling across microphones.

7.3.7 Signal-Chain Processing

The PCM1840 signal chain is comprised of very-low-noise, high-performance, and low-power analog blocks and highly flexible and programmable digital processing blocks. The high performance and flexibility combined with a compact package makes the PCM1840 optimized for a variety of end-equipments and applications that require multichannel audio capture. 図 22 shows a conceptual block diagram that highlights the various building blocks used in the signal chain, and how the blocks interact in the signal chain.

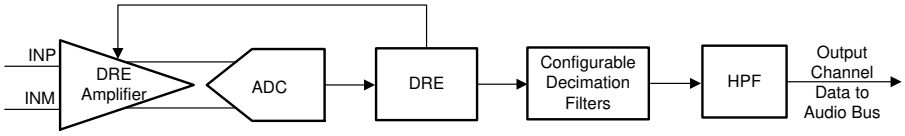


図 22. Signal-Chain Processing Flowchart

The front-end dynamic range enhancer (DRE) gain amplifier is very low noise, with a 123-dB dynamic range performance. Along with a low-noise and low-distortion, multibit, delta-sigma ADC, the front-end DRE gain amplifier enables the PCM1840 to record a far-field audio signal with very high fidelity, both in quiet and loud environments. Moreover, the ADC architecture has inherent antialias filtering with a high rejection of out-of-band frequency noise around multiple modulator frequency components. Therefore, the device prevents noise from aliasing into the audio band during ADC sampling. Further on in the signal chain, an integrated, high-performance multistage digital decimation filter sharply cuts off any out-of-band frequency noise with high stop-band attenuation.

The device supports an input signal bandwidth up to 80 kHz, which allows the high-frequency non-audio signal to be recorded by using a 176.4-kHz (or higher) sample rate.

7.3.7.1 Digital High-Pass Filter

To remove the DC offset component and attenuate the undesired low-frequency noise content in the record data, the device supports a fixed high-pass filter (HPF) with –3-dB cut-off frequency of 0.00025 × f_S. The HPF is not a channel-independent filter but is globally applicable for all the ADC channels. This HPF is constructed using the first-order infinite impulse response (IIR) filter, and is efficient enough to filter out possible DC components of the signal. 表 6 shows the fixed –3-dB cutoff frequency value. 図 23 shows a frequency response plot for the HPF filter.

表 6. HPF Cutoff Frequency Value

-3-dB CUTOFF FREQUENCY VALUE	-3-dB CUTTOFF FREQUENCY AT 16 kHz SAMPLE RATE	-3-dB CUTTOFF FREQUENCY AT 48 kHz SAMPLE RATE
0.00025 × f_S	4 Hz	12 Hz

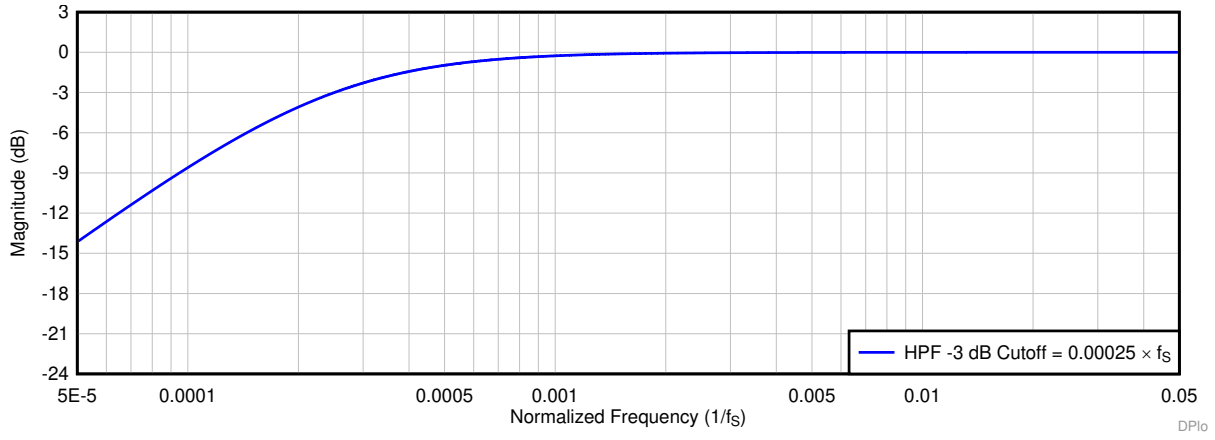


図 23. HPF Filter Frequency Response Plot

7.3.7.2 Configurable Digital Decimation Filters

The device record channel includes a high dynamic range, built-in digital decimation filter to process the oversampled data from the multibit delta-sigma (ΔΣ) modulator to generate digital data at the same Nyquist sampling rate as the FSYNC rate. The decimation filter can be chosen from two different types only in slave mode, depending on the required frequency response, group delay, and phase linearity requirements for the target application. The selection of the decimation filter option can be done by the MD0 pin. 表 7 shows the decimation filter mode selection for the record channel.

表 7. Decimation Filter Mode Selection for the Record Channel

MD0	DECIMATION FILTER MODE SELECTION (Supported Only in Slave Mode)
LOW	Linear phase filters are used for the decimation in slave mode. For master mode, the device always use linear phase filters for the decimation.
HIGH	Low latency filters are used for the decimation in slave mode. For master mode, the device always use linear phase filters for the decimation.

7.3.7.2.1 Linear Phase Filters

The linear phase decimation filters are the default filters set by the device and can be used for all applications that require a perfect linear phase with zero-phase deviation within the pass-band specification of the filter. The filter performance specifications and various plots for all supported output sampling rates are listed in this section.

7.3.7.2.1.1 Sampling Rate: 8 kHz or 7.35 kHz

図 24 and 図 25 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 8 kHz or 7.35 kHz. 表 8 lists the specifications for a decimation filter with an 8-kHz or 7.35-kHz sampling rate.

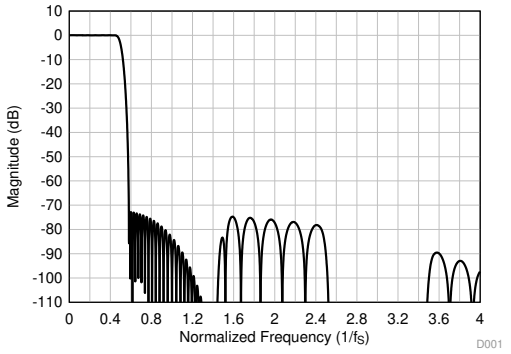


図 24. Linear Phase Decimation Filter Magnitude Response

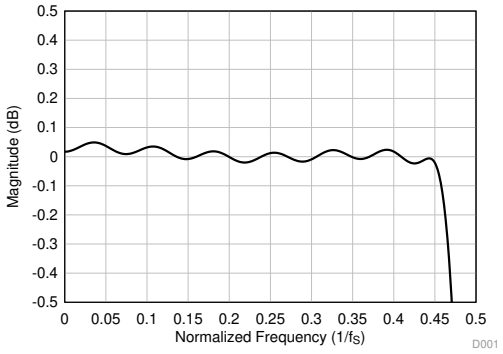


図 25. Linear Phase Decimation Filter Pass-Band Ripple

表 8. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	72.7			dB
	Frequency range is 4 × f_S onwards	81.2			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		17.1		1/f_S

7.3.7.2.1.2 Sampling Rate: 16 kHz or 14.7 kHz

図 26 and 図 27 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 16 kHz or 14.7 kHz. 表 9 lists the specifications for a decimation filter with an 16-kHz or 14.7-kHz sampling rate.

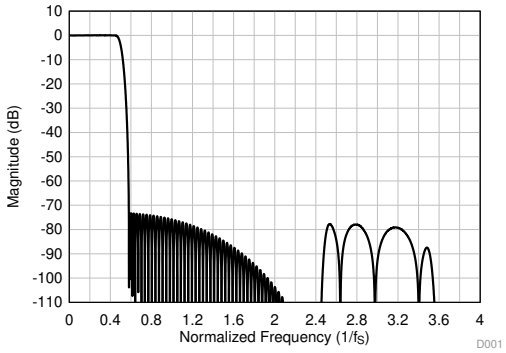


図 26. Linear Phase Decimation Filter Magnitude Response

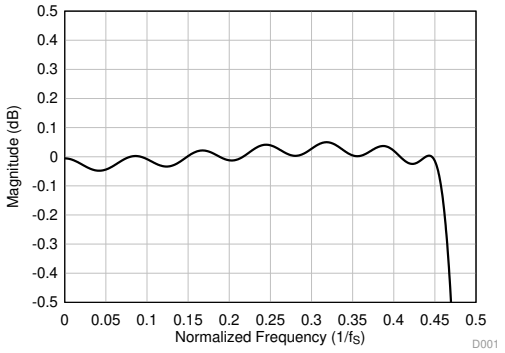


図 27. Linear Phase Decimation Filter Pass-Band Ripple

表 9. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	73.3			dB
	Frequency range is 4 × f_S onwards	95.0			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		15.7		1/f_S

7.3.7.2.1.3 Sampling Rate: 24 kHz or 22.05 kHz

図 28 and 図 29 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 24 kHz or 22.05 kHz. 表 10 lists the specifications for a decimation filter with an 24-kHz or 22.05-kHz sampling rate.

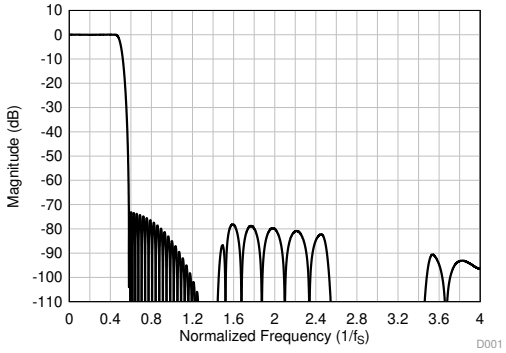


図 28. Linear Phase Decimation Filter Magnitude Response

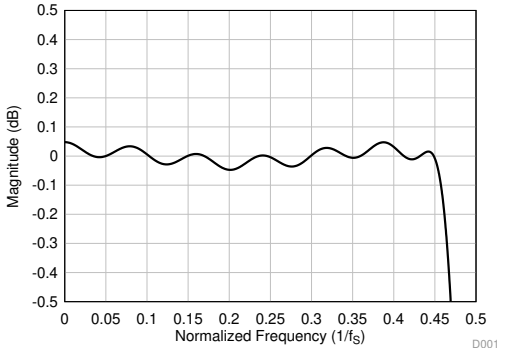


図 29. Linear Phase Decimation Filter Pass-Band Ripple

表 10. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	73.0			dB
	Frequency range is 4 × f_S onwards	96.4			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		16.6		1/f_S

7.3.7.2.1.4 Sampling Rate: 32 kHz or 29.4 kHz

図 30 and 図 31 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 32 kHz or 29.4 kHz. 表 11 lists the specifications for a decimation filter with an 32-kHz or 29.4-kHz sampling rate.

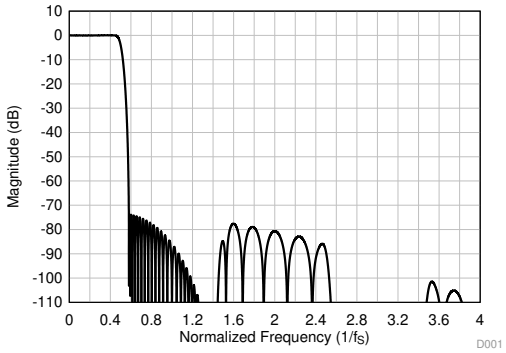


図 30. Linear Phase Decimation Filter Magnitude Response

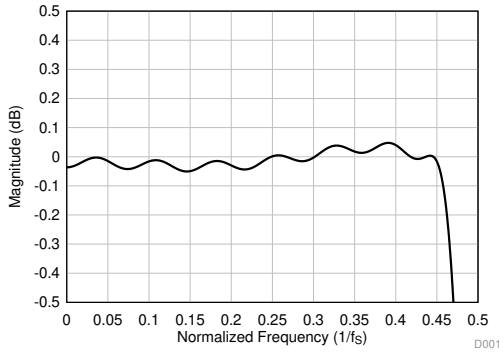


図 31. Linear Phase Decimation Filter Pass-Band Ripple

表 11. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	73.7			dB
	Frequency range is 4 × f_S onwards	107.2			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		16.9		1/f_S

7.3.7.2.1.5 Sampling Rate: 48 kHz or 44.1 kHz

図 32 and 図 33 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 48 kHz or 44.1 kHz. 表 12 lists the specifications for a decimation filter with an 48-kHz or 44.1-kHz sampling rate.

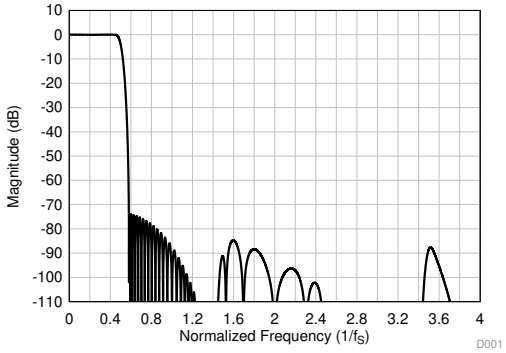


図 32. Linear Phase Decimation Filter Magnitude Response

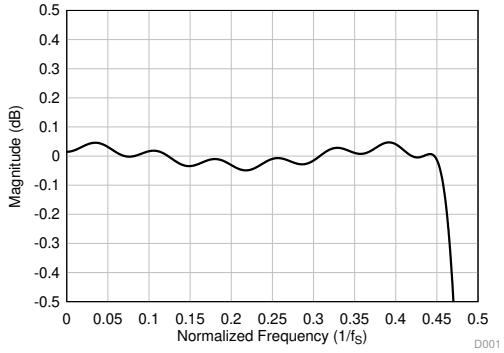


図 33. Linear Phase Decimation Filter Pass-Band Ripple

表 12. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	73.8			dB
	Frequency range is 4 × f_S onwards	98.1			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		17.1		1/f_S

7.3.7.2.1.6 Sampling Rate: 96 kHz or 88.2 kHz

図 34 and 図 35 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 96 kHz or 88.2 kHz. 表 13 lists the specifications for a decimation filter with an 96-kHz or 88.2-kHz sampling rate.

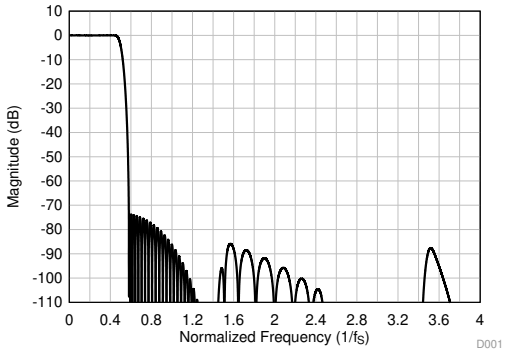


図 34. Linear Phase Decimation Filter Magnitude Response

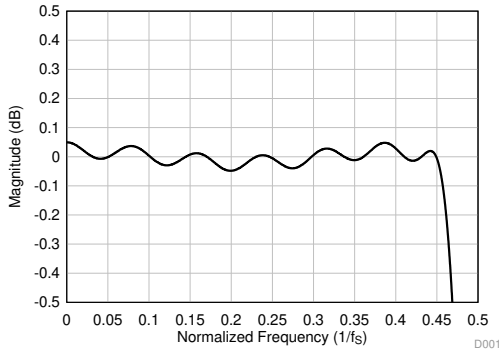


図 35. Linear Phase Decimation Filter Pass-Band Ripple

表 13. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.454 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.58 × f_S to 4 × f_S	73.6			dB
	Frequency range is 4 × f_S onwards	97.9			
Group delay or latency	Frequency range is 0 to 0.454 × f_S		17.1		1/f_S

7.3.7.2.1.7 Sampling Rate: 192 kHz or 176.4 kHz

図 36 and 図 37 respectively show the magnitude response and the pass-band ripple for a decimation filter with a sampling rate of 192 kHz or 176.4 kHz. 表 14 lists the specifications for a decimation filter with an 192-kHz or 176.4-kHz sampling rate.

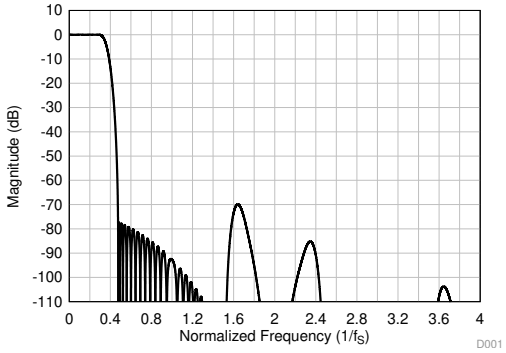


図 36. Linear Phase Decimation Filter Magnitude Response

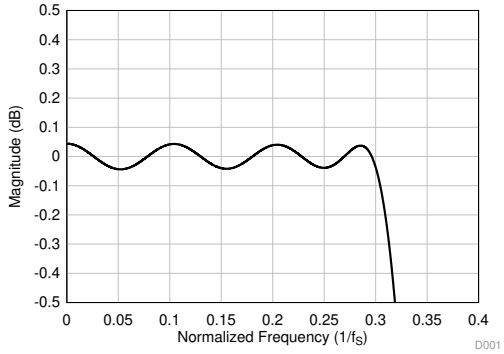


図 37. Linear Phase Decimation Filter Pass-Band Ripple

表 14. Linear Phase Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.3 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.473 × f_S to 4 × f_S	70.0			dB
	Frequency range is 4 × f_S onwards	111.0			
Group delay or latency	Frequency range is 0 to 0.3 × f_S		11.9		1/f_S

7.3.7.2.2 Low-Latency Filters

For applications where low latency with minimal phase deviation (within the audio band) is critical, the low-latency decimation filters on the PCM1840 can be used. The device supports these filters with a group delay of approximately seven samples with an almost linear phase response within the 0.365 × f_S frequency band. This section provides the filter performance specifications and various plots for all supported output sampling rates for the low-latency filters.

7.3.7.2.2.1 Sampling Rate: 16 kHz or 14.7 kHz

図 38 shows the magnitude response and 図 39 shows the pass-band ripple and phase deviation for a decimation filter with a sampling rate of 16 kHz or 14.7 kHz. 表 15 lists the specifications for a decimation filter with a 16-kHz or 14.7-kHz sampling rate.

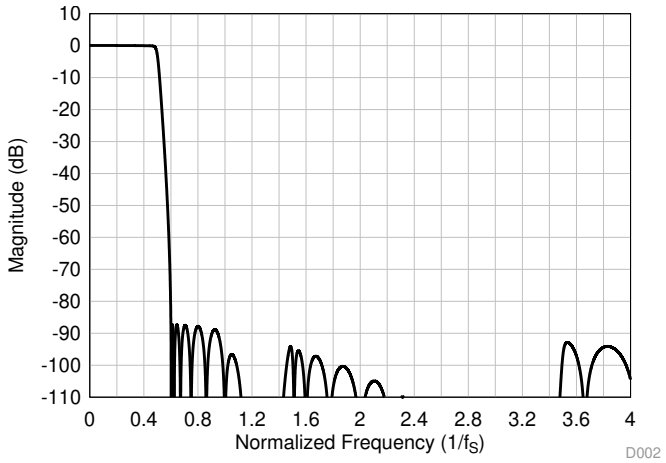


図 38. Low-Latency Decimation Filter Magnitude Response

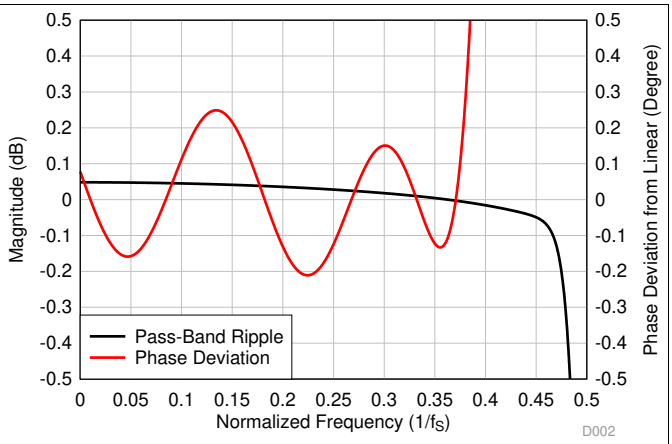


図 39. Low-Latency Decimation Filter Pass-Band Ripple and Phase Deviation

表 15. Low-Latency Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.451 × f_S	–0.05		0.05	dB
Stop-band attenuation	Frequency range is 0.61 × f_S onwards	87.3			dB
Group delay or latency	Frequency range is 0 to 0.363 × f_S		7.6		1/f_S
Group delay deviation	Frequency range is 0 to 0.363 × f_S	–0.022		0.022	1/f_S
Phase deviation	Frequency range is 0 to 0.363 × f_S	–0.21		0.25	Degrees

7.3.7.2.2.2 Sampling Rate: 24 kHz or 22.05 kHz

図 40 shows the magnitude response and 図 41 shows the pass-band ripple and phase deviation for a decimation filter with a sampling rate of 24 kHz or 22.05 kHz. 表 16 lists the specifications for a decimation filter with a 24-kHz or 22.05-kHz sampling rate.

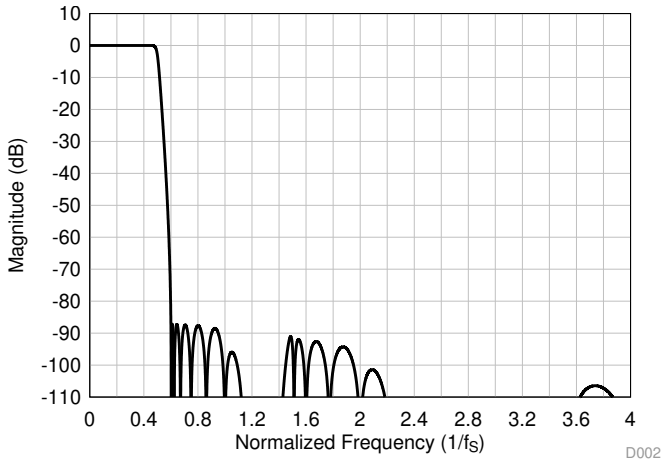


図 40. Low-Latency Decimation Filter Magnitude Response

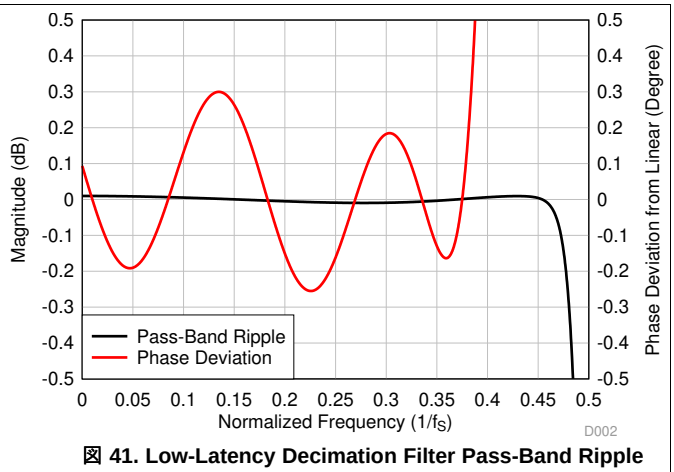


図 41. Low-Latency Decimation Filter Pass-Band Ripple and Phase Deviation

表 16. Low-Latency Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.459 × f_S	–0.01		0.01	dB
Stop-band attenuation	Frequency range is 0.6 × f_S onwards	87.2			dB
Group delay or latency	Frequency range is 0 to 0.365 × f_S		7.5		$1/f_S$
Group delay deviation	Frequency range is 0 to 0.365 × f_S	–0.026		0.026	$1/f_S$
Phase deviation	Frequency range is 0 to 0.365 × f_S	–0.26		0.30	Degrees

7.3.7.2.2.3 Sampling Rate: 32 kHz or 29.4 kHz

図 42 shows the magnitude response and 図 43 shows the pass-band ripple and phase deviation for a decimation filter with a sampling rate of 32 kHz or 29.4 kHz. 表 17 lists the specifications for a decimation filter with a 32-kHz or 29.4-kHz sampling rate.

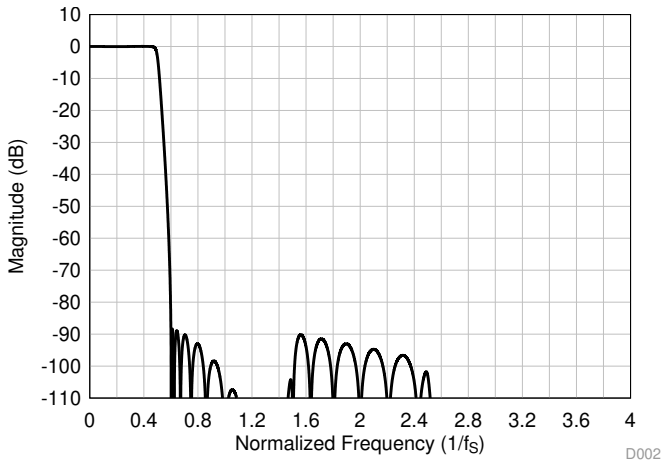


図 42. Low-Latency Decimation Filter Magnitude Response

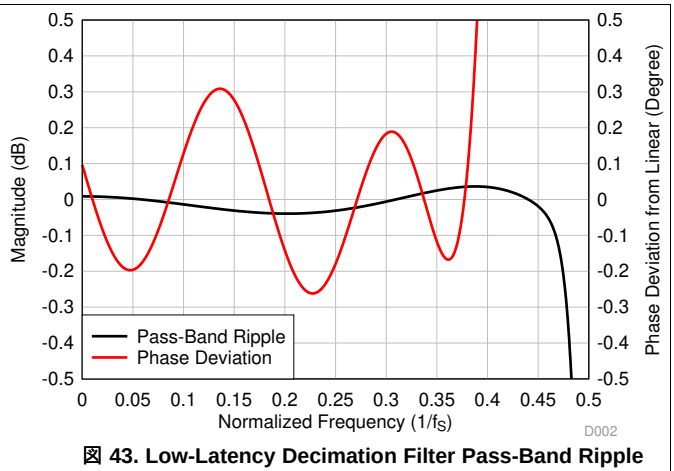


図 43. Low-Latency Decimation Filter Pass-Band Ripple and Phase Deviation

表 17. Low-Latency Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.457 × f_S	–0.04		0.04	dB
Stop-band attenuation	Frequency range is 0.6 × f_S onwards	88.3			dB
Group delay or latency	Frequency range is 0 to 0.368 × f_S		8.7		$1/f_S$
Group delay deviation	Frequency range is 0 to 0.368 × f_S	–0.026		0.026	$1/f_S$
Phase deviation	Frequency range is 0 to 0.368 × f_S	–0.26		0.31	Degrees

7.3.7.2.2.4 Sampling Rate: 48 kHz or 44.1 kHz

図 44 shows the magnitude response and 図 45 shows the pass-band ripple and phase deviation for a decimation filter with a sampling rate of 48 kHz or 44.1 kHz. 表 18 lists the specifications for a decimation filter with a 48-kHz or 44.1-kHz sampling rate.

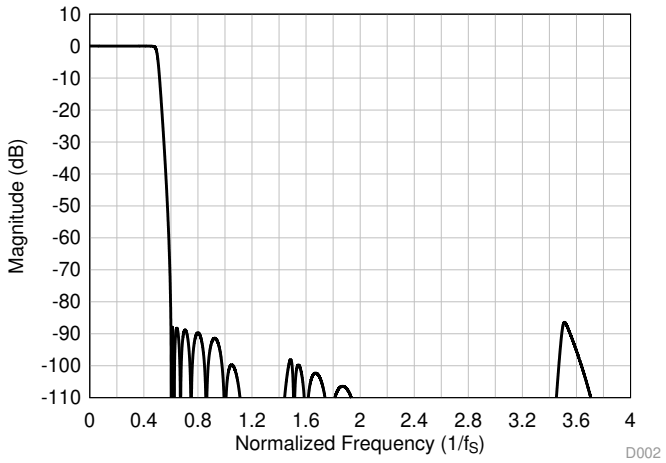


図 44. Low-Latency Decimation Filter Magnitude Response

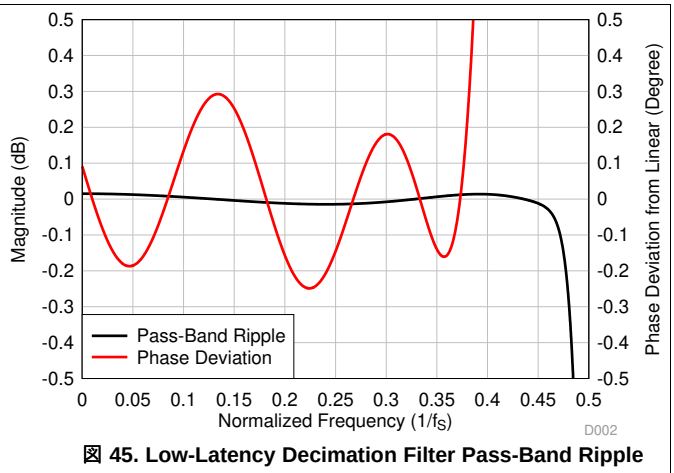


図 45. Low-Latency Decimation Filter Pass-Band Ripple and Phase Deviation

表 18. Low-Latency Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.452 × f_S	–0.015		0.015	dB
Stop-band attenuation	Frequency range is 0.6 × f_S onwards	86.4			dB
Group delay or latency	Frequency range is 0 to 0.365 × f_S		7.7		$1/f_S$
Group delay deviation	Frequency range is 0 to 0.365 × f_S	–0.027		0.027	$1/f_S$
Phase deviation	Frequency range is 0 to 0.365 × f_S	–0.25		0.30	Degrees

7.3.7.2.2.5 Sampling Rate: 96 kHz or 88.2 kHz

図 46 shows the magnitude response and 図 47 shows the pass-band ripple and phase deviation for a decimation filter with a sampling rate of 96 kHz or 88.2 kHz. 表 19 lists the specifications for a decimation filter with a 96-kHz or 88.2-kHz sampling rate.

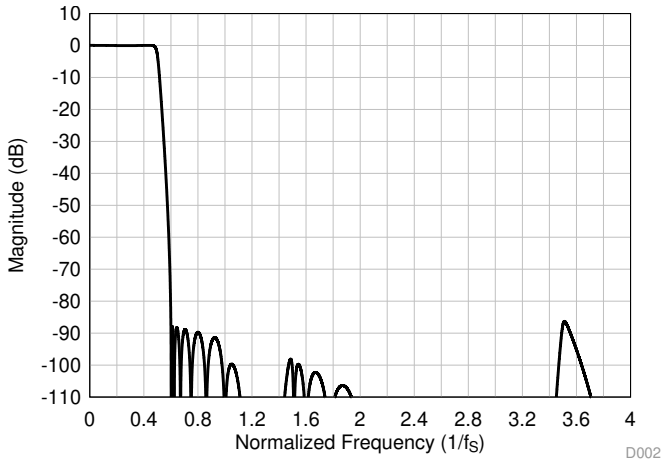


図 46. Low-Latency Decimation Filter Magnitude Response

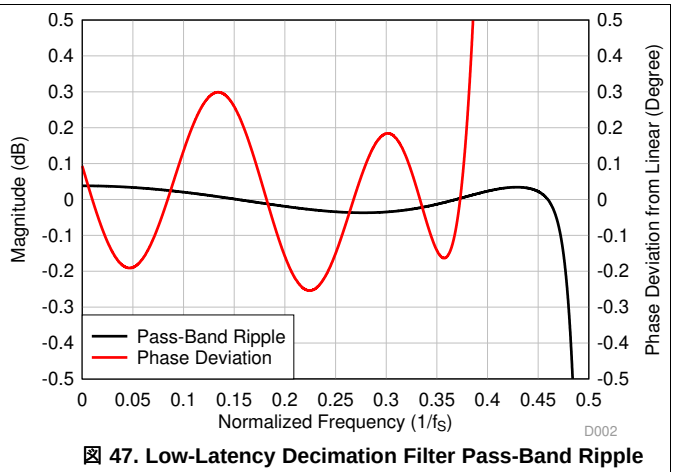


図 47. Low-Latency Decimation Filter Pass-Band Ripple and Phase Deviation

表 19. Low-Latency Decimation Filter Specifications

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Pass-band ripple	Frequency range is 0 to 0.466 × f_S	–0.04		0.04	dB
Stop-band attenuation	Frequency range is 0.6 × f_S onwards	86.3			dB
Group delay or latency	Frequency range is 0 to 0.365 × f_S		7.7		$1/f_S$
Group delay deviation	Frequency range is 0 to 0.365 × f_S	–0.027		0.027	$1/f_S$
Phase deviation	Frequency range is 0 to 0.365 × f_S	–0.26		0.30	Degrees

7.3.8 Dynamic Range Enhancer (DRE)

The device integrates an ultra-low noise front-end DRE gain amplifier with 123-dB dynamic range performance with a low-noise, low-distortion, multibit delta-sigma (ΔΣ) ADC with a 108-dB dynamic range. The dynamic range enhancer (DRE) is a digitally assisted algorithm to boost the overall channel performance. The DRE monitors the incoming signal amplitude and accordingly adjusts the internal DRE amplifier gain automatically. The DRE achieves a complete-channel dynamic range as high as 123 dB. At a system level, the DRE scheme enables far-field, high-fidelity recording of audio signals in very quiet environments and low-distortion recording in loud environments.

The DRE can be enable only in slave mode by driving high to the MD1 pin. 表 20 shows the DRE selection for the record channel.

表 20. DRE Selection for the Record Channel

MD1	DRE SELECTION (Supported Only in Slave Mode)
LOW	DRE is disabled in slave mode. For master mode, DRE is always disabled.
HIGH	DRE is enabled with DRE_LVL = –36 dB and DRE_MAXGAIN = 24 dB in slave mode. For master mode, DRE is always disabled.

This algorithm is implemented with very low latency and all signal chain blocks are designed to minimize any audible artifacts that may occur resulting from dynamic gain modulation. The target signal threshold level, DRE_LVL, at which DRE is triggered is fixed to the –36-dB input signal level. The DRE gain range can be dynamically modulated by using DRE_MAXGAIN, which is fixed to 24 dB to maximize the benefit of the DRE in real-world applications and to minimize any audible artifacts.

Enabling the DRE for processing increases the power consumption of the device because of increased signal processing. Therefore, disable the DRE for low-power critical applications. Furthermore, the DRE is not supported for output sample rates greater than 48 kHz.

7.4 Device Functional Modes

7.4.1 Hardware Shutdown

The device enters hardware shutdown mode when the SHDNZ pin is asserted low or the AVDD supply voltage is not applied to the device. In hardware shutdown mode, the device consumes the minimum quiescent current from the AVDD supply. If the SHDNZ pin is asserted low when the device is in active mode, the device ramps down volume on the record data, powers down the analog and digital blocks, and puts the device into hardware shutdown mode in 25 ms (typical).

7.4.2 Active Mode

In the hardware shutdown state, when the SHDNZ pin goes high, the device starts the internal boot-up sequence and then enters into active mode in less than 20 ms (typical). Assert the SHDNZ pin high only when the IOVDD supply settles to a steady voltage level and all hardware control pins (MSZ, MD0, MD1, FMT0, and FMT1) are driven to the voltage level for the device desired mode of operation.

In active mode, when the audio clocks are available, the device powers up all the ADC channels and starts transmitting the data over the audio serial interface. If the clocks are stopped then the device auto powers down the ADC channels.

8 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The PCM1840 is a multichannel, high-performance audio analog-to-digital converter (ADC) that supports output sample rates of up to 192 kHz. The device supports up to four analog microphones for simultaneous recording applications.

The PCM1840 configuration is supported using various hardware pin control options. The device supports a highly flexible, audio serial interface (TDM, I^2S, and LJ) to transmit audio data seamlessly in the system across devices.

8.2 Typical Application

図 48 shows a typical configuration of the PCM1840 for an application using four analog microelectrical-mechanical system (MEMS) microphones for simultaneous recording operation with a time-division multiplexing (TDM) audio data slave interface. For best distortion performance, use input AC-coupling capacitors with a low-voltage coefficient.

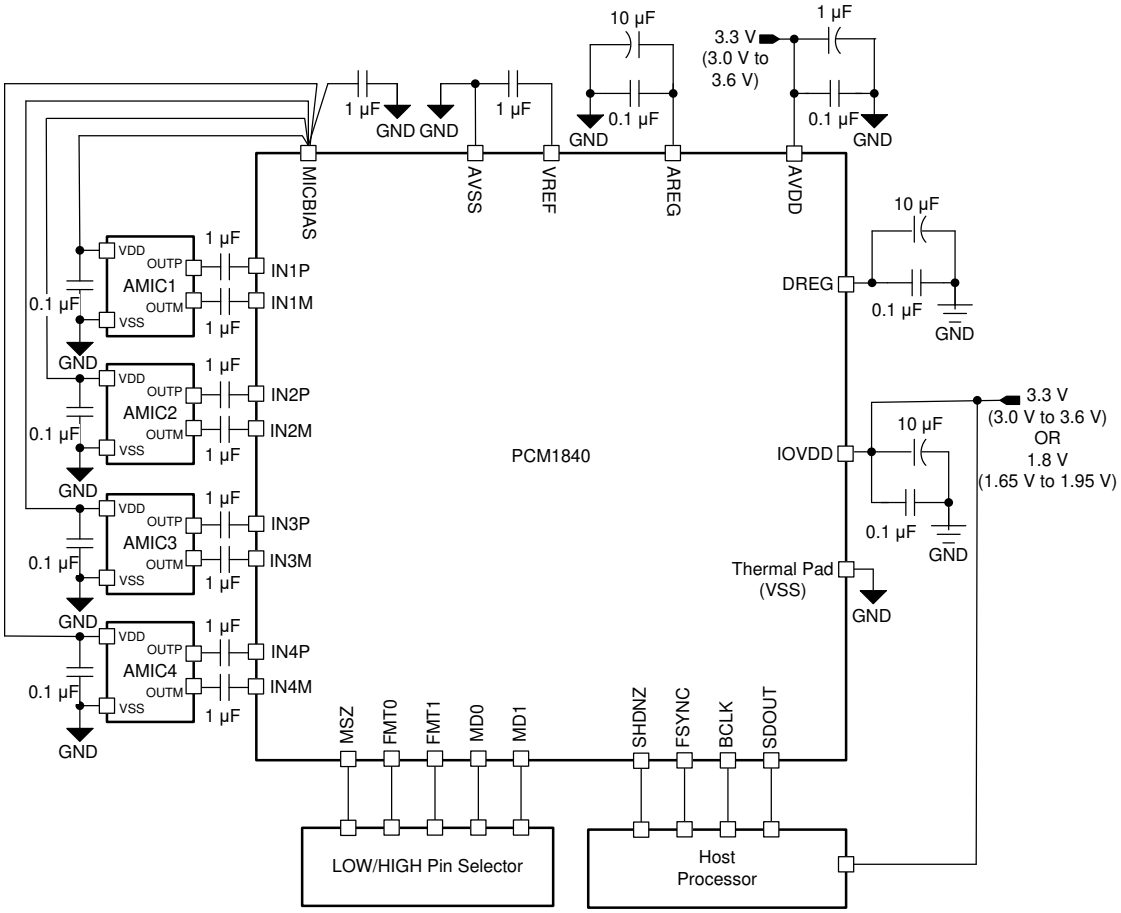


図 48. Four-Channel Analog Microphone Recording Diagram for 3.3-V AVDD Operation

Typical Application (continued)

8.2.1 Design Requirements

表 21 lists the design parameters for this application.

表 21. Design Parameters

KEY PARAMETER	SPECIFICATION: 3.3-V AVDD OPERATION
AVDD	3.3 V
AVDD supply current consumption	> 23 mA (PLL on, four-channel recording, f_S = 48 kHz)
IOVDD	1.8 V or 3.3 V
Maximum MICBIAS current	10 mA (MICBIAS voltage is the same as VREF)

8.2.2 Detailed Design Procedure

This section describes the necessary steps to configure the PCM1840 for this specific application. The following steps provide a sequence of items that must be executed in the time between powering the device up and reading data from the device or transitioning from one mode to another mode of operation.

1. Apply power to the device:
   a. Power-up the IOVDD and AVDD power supplies, keeping the SHDNZ pin voltage low
   b. The device now goes into hardware shutdown mode (ultra-low-power mode < 1 µA)
2. Transition from hardware shutdown mode to active mode whenever required for the recording operation:
   a. Connect the MSZ, FMT0, and FMT1 pins voltage low to configure the device in 4-channel TDM slave mode
   b. Release SHDNZ only when the IOVDD and AVDD power supplies settle to the steady-state operating voltage
   c. Apply FSYNC and BCLK with the desired output sample rates and the BCLK to FSYNC ratio

      This specific step can be done at any point in the sequence after step a

      See the *Phase-Locked Loop (PLL) and Clock Generation* section for supported sample rates and the BCLK to FSYNC ratio
   d. The device recording data are now sent to the host processor via the TDM audio serial data bus
3. Assert the SHDNZ pin low to enter hardware shutdown mode (again) at any time
4. Follow step 2 onwards to exit hardware shutdown mode (again)

8.2.3 Application Curves

Measurements are done on the EVM by feeding the device analog input signal using audio precision and with a 3.3-V AVDD supply.

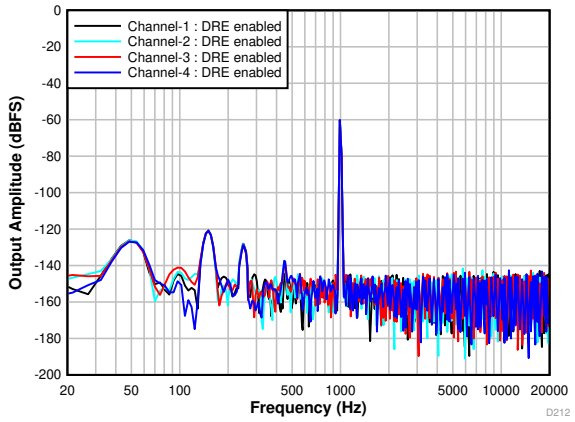


図 49. FFT With a –60-dBr Input With DRE Enabled

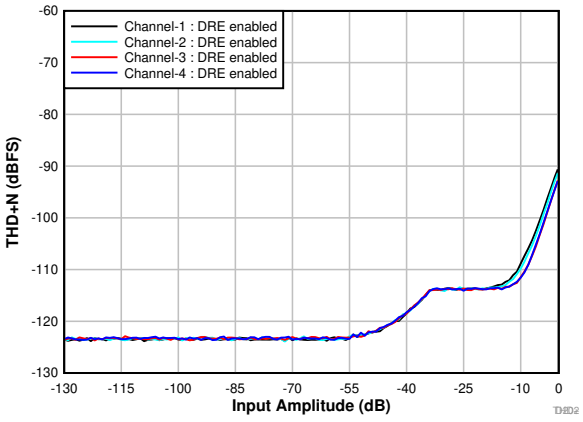


図 50. THD+N vs Input Amplitude With DRE Enabled

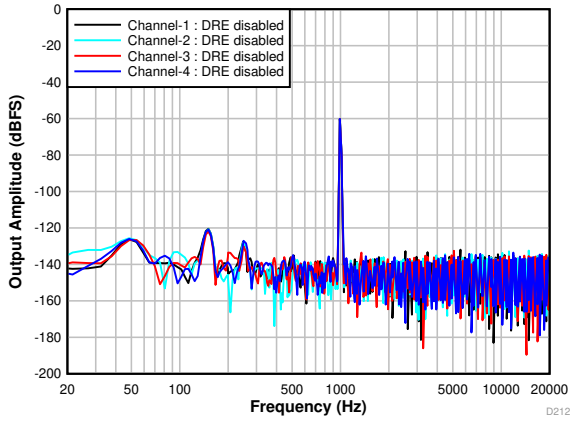


図 51. FFT With a –60-dBr Input With DRE Disabled

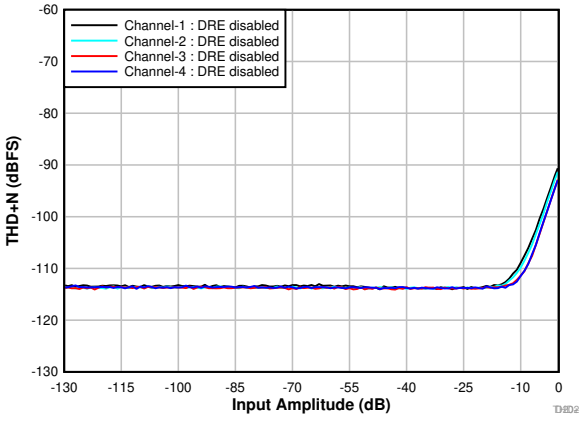


図 52. THD+N vs Input Amplitude With DRE Disabled

9 Power Supply Recommendations

The power-supply sequence between the IOVDD and AVDD rails can be applied in any order. However, keep the SHDNZ pin low until the IOVDD supply voltage settles to a stable and supported operating voltage range. After all supplies are stable, set the SHDNZ pin high to initialize the device. Assert the SHDNZ pin high only when all hardware control pins (MSZ, MD0, MD1, FMT0, and FMT1) are driven to the voltage level for the device desired mode of operation.

For the supply power-up requirement, t_1 and t_2 must be at least 100 µs. For the supply power-down requirement, t_3 and t_4 must be at least 10 ms. This timing (as shown in 図 53) allows the device to ramp down the volume on the record data, power down the analog and digital blocks, and put the device into hardware shutdown mode.

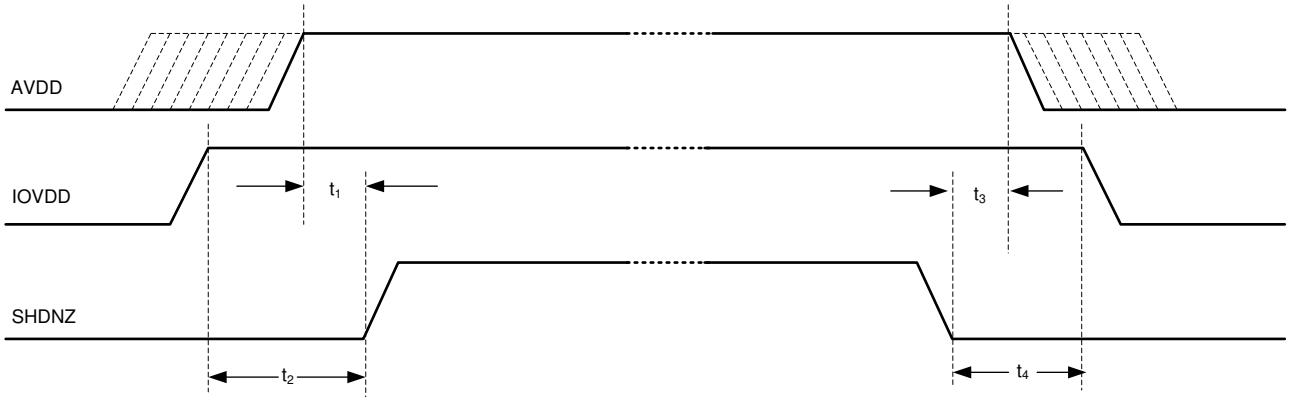


図 53. Power-Supply Sequencing Requirement Timing Diagram

Make sure that the supply ramp rate is slower than 1 V/µs and that the wait time between a power-down and a power-up event is at least 100 ms.

The PCM1840 supports a single AVDD supply operation by integrating an on-chip digital regulator, DREG, and an analog regulator, AREG. However, if the AVDD voltage is less than 1.98 V in the system, then short the AREG and AVDD pins onboard.

10 Layout

10.1 Layout Guidelines

Each system design and printed circuit board (PCB) layout is unique. The layout must be carefully reviewed in the context of a specific PCB design. However, the following guidelines can optimize the device performance:

- Connect the thermal pad to ground. Use a via pattern to connect the device thermal pad, which is the area directly under the device, to the ground planes. This connection helps dissipate heat from the device.
- The decoupling capacitors for the power supplies must be placed close to the device pins.
- Route the analog differential audio signals differentially on the PCB for better noise immunity. Avoid crossing digital and analog signals to prevent undesirable crosstalk.
- The device internal voltage references must be filtered using external capacitors. Place the filter capacitors near the VREF pin for optimal performance.
- Directly tap the MICBIAS pin to avoid common impedance when routing the biasing or supply traces for multiple microphones to avoid coupling across microphones.
- Directly short the VREF and MICBIAS external capacitors ground terminal to the AVSS pin without using any vias for this connection trace.
- Place the MICBIAS capacitor (with low equivalent series resistance) close to the device with minimal trace impedance.
- Use ground planes to provide the lowest impedance for power and signal current between the device and the decoupling capacitors. Treat the area directly under the device as a central ground area for the device, and all device grounds must be connected directly to that area.

10.2 Layout Example

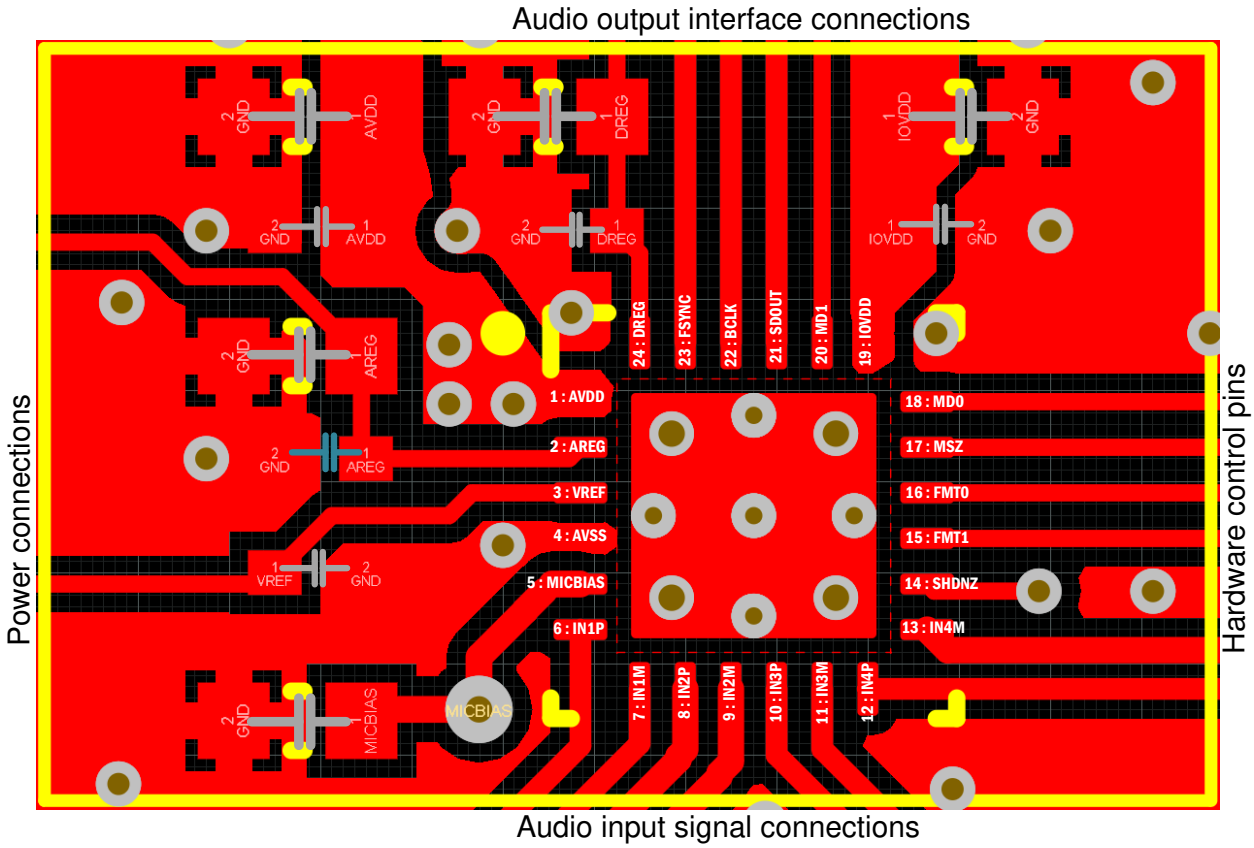


図 54. Example Layout

11 デバイスおよびドキュメントのサポート

11.1 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、ti.comのデバイス製品フォルダを開いてください。右上の「アラートを受け取る」をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取れます。変更の詳細については、修正されたドキュメントに含まれている改訂履歴をご覧ください。

11.2 コミュニティ・リソース

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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11.3 商標

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11.4 静電気放電に関する注意事項

すべての集積回路は、適切なESD保護方法を用いて、取扱いと保存を行うようにして下さい。

静電気放電はわずかな性能の低下から完全なデバイスの故障に至るまで、様々な損傷を与えます。高精度の集積回路は、損傷に対して敏感であり、極めてわずかなパラメータの変化により、デバイスに規定された仕様に適合しなくなる場合があります。

11.5 Glossary

SLYZ022 — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

12 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスについて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
PCM1840IRTWR	ACTIVE	WQFN	RTW	24	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	PCM1840	Samples
PCM1840IRTWT	ACTIVE	WQFN	RTW	24	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	PCM1840	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".
RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.
Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

GENERIC PACKAGE VIEW

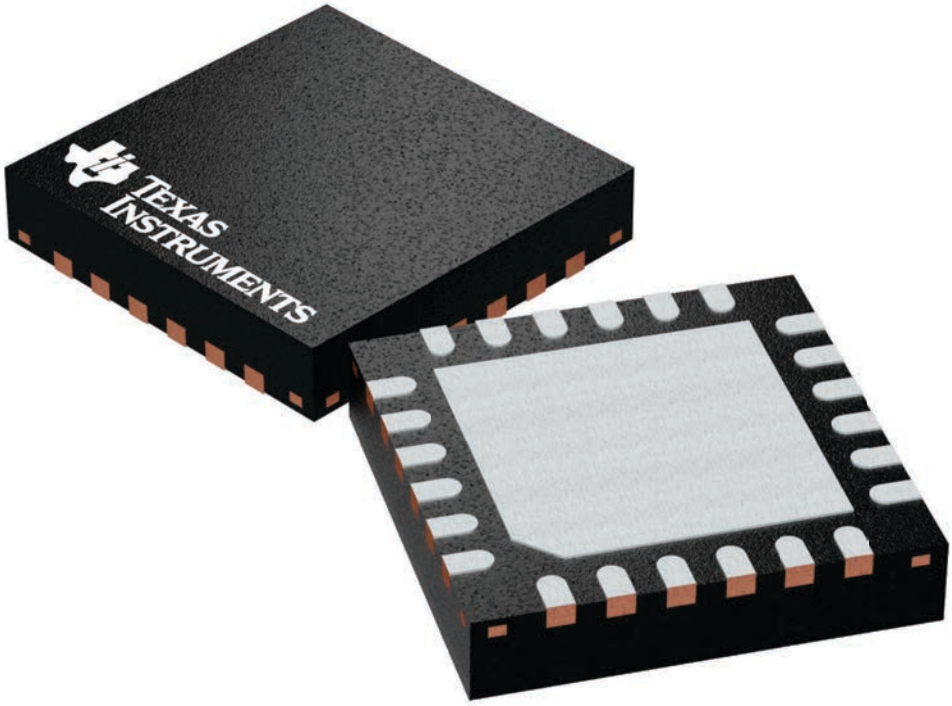
RTW 24

WQFN - 0.8 mm max height

4 x 4, 0.5 mm pitch

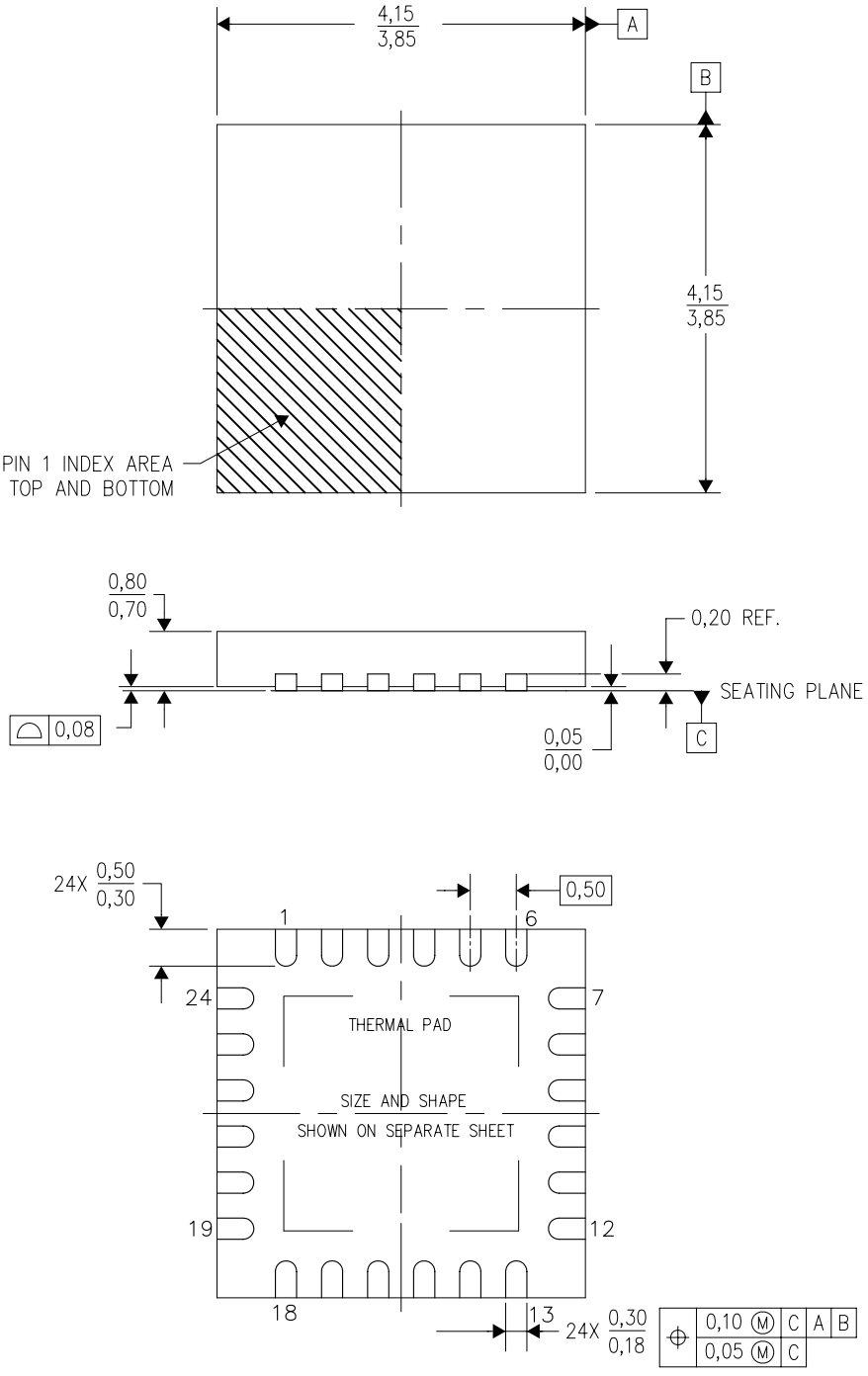
PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



4224801/A

RTW (S–PWQFN–N24) PLASTIC QUAD FLATPACK NO–LEAD



NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Quad Flatpack, No–Leads (QFN) package configuration.
D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
F. Falls within JEDEC MO–220.

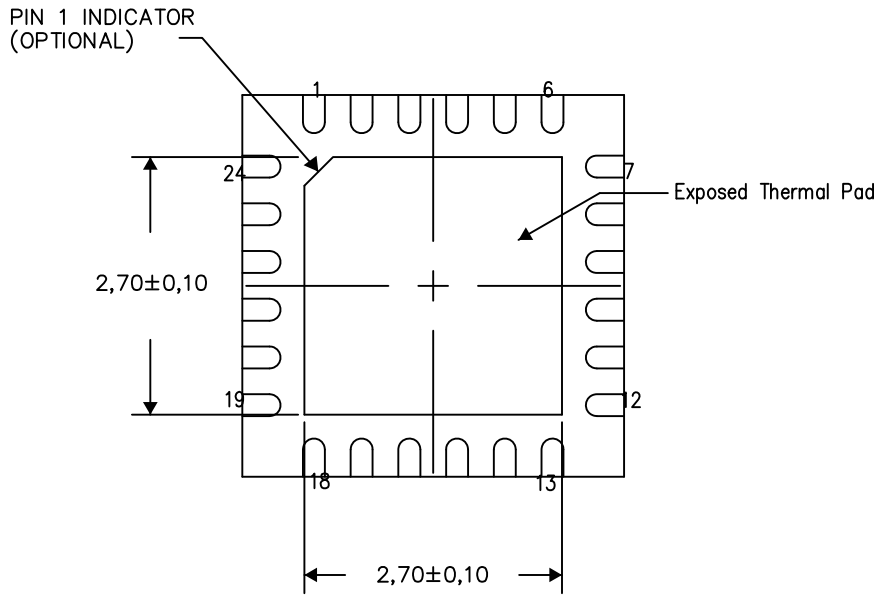
RTW (S–PWQFN–N24) PLASTIC QUAD FLATPACK NO–LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No–Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



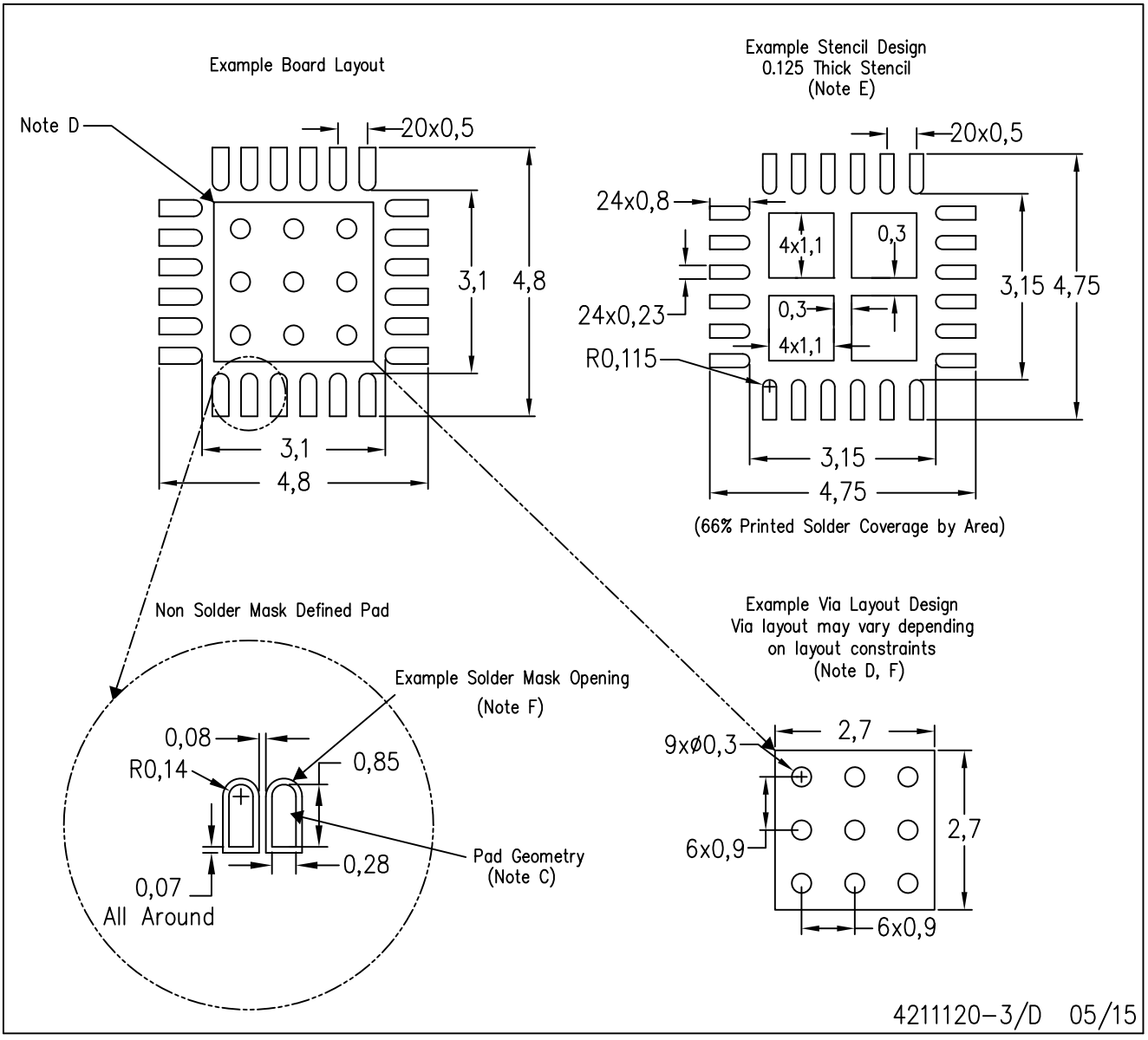
Bottom View

Exposed Thermal Pad Dimensions

4206249–5/P 05/15

NOTES: A. All linear dimensions are in millimeters

RTW (S–PWQFN–N24) PLASTIC QUAD FLATPACK NO–LEAD



NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Publication IPC–7351 is recommended for alternate designs.
D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat–Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.

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